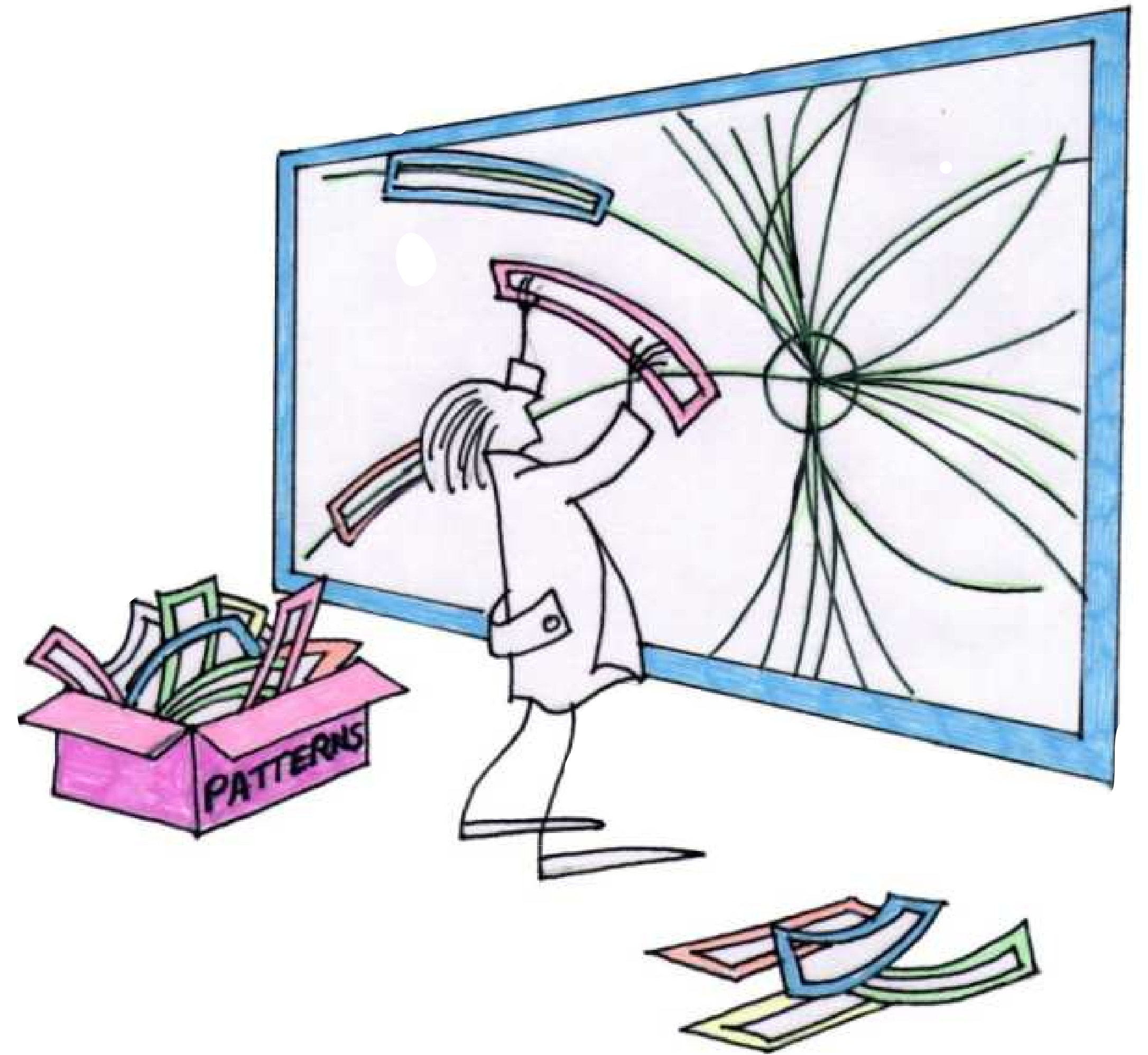


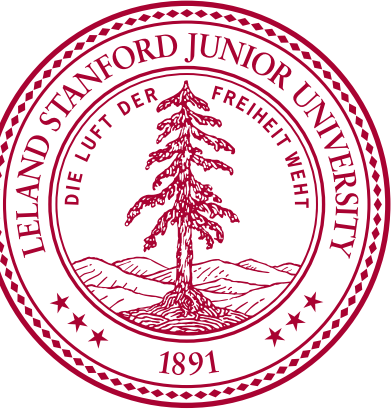
THE FTK EXPERIENCE

LAUREN TOMPKINS
MU2E-II TDAQ WORKSHOP
SEPT 14 2020



Stanford
University

OUTLINE

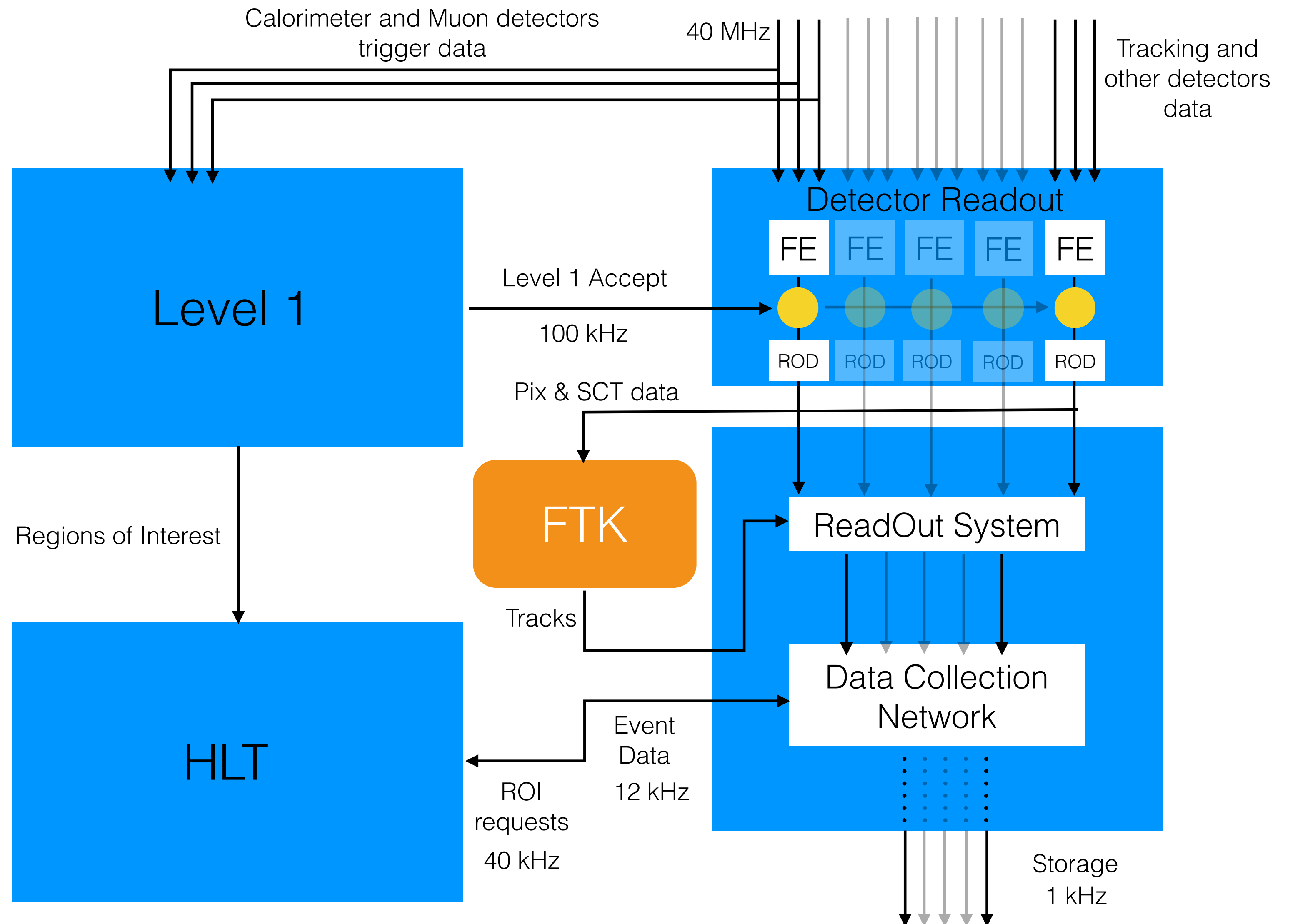


- FTK in context
- How it worked: FTK Design & Performance
- Lessons Learned

FTK IN THE ATLAS TRIGGER SYSTEM

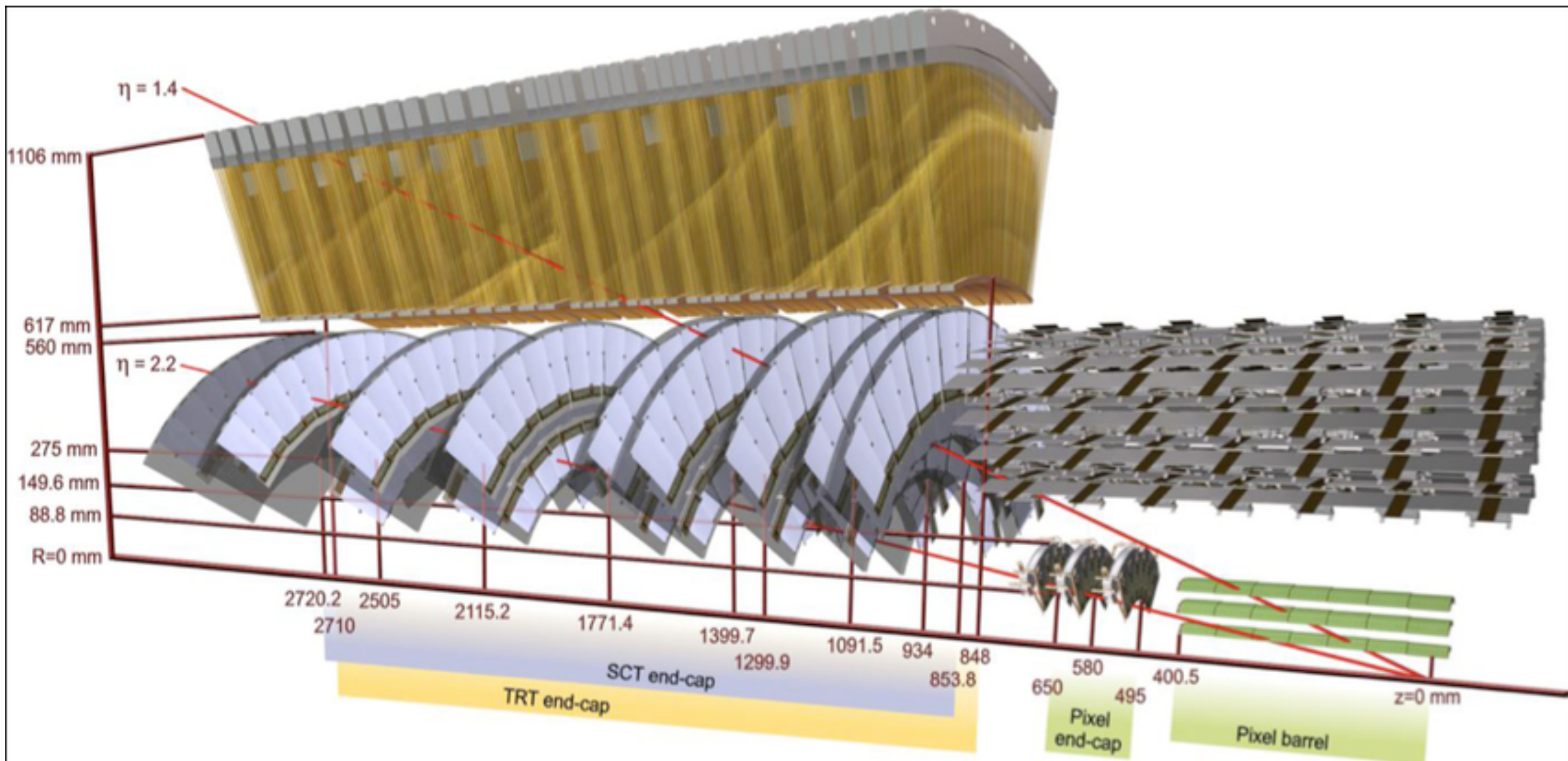
- FTK design:

- Co-processor for the ATLAS HLT
- Provide full detector silicon tracking for every L1 accepted event ($p_T > 1 \text{ GeV}$, $|\eta| < 2.5$ @ 100kHz)
- Hadronic final states
- Long-lived final states
- B-physics triggers
- Pile-up mitigation, beam spot
- System design studies at pile-up of 70

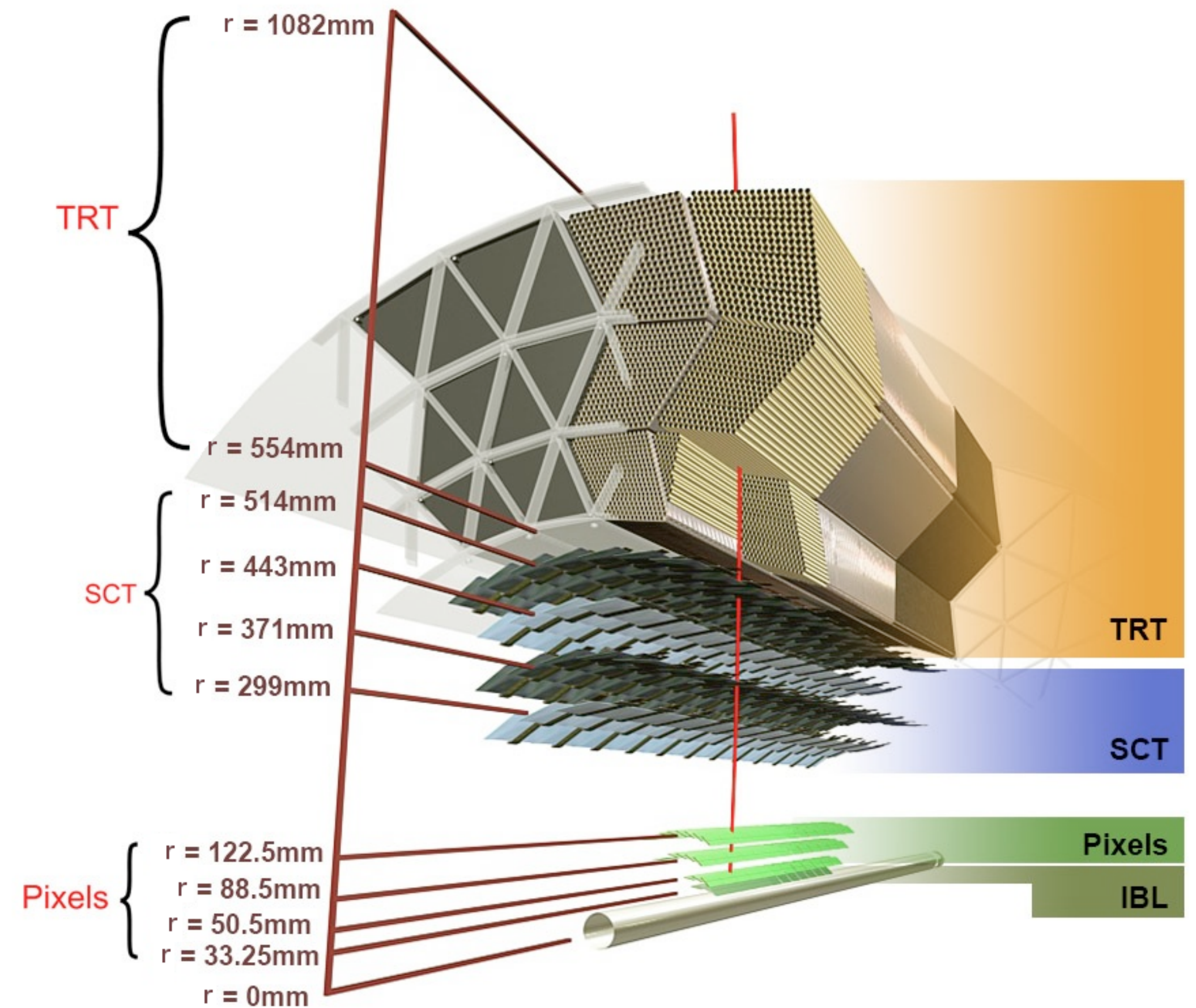


ATLAS TRACKERS

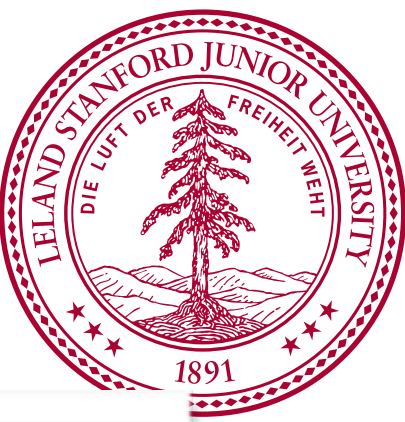
- Pixels: 50x200 microns, 4 layers, ~100 million channels
- Strips (SCT): 80micron strips, double sided axial/stereo, ~4 million channels
- 2T solenoidal magnetic field



+ IBL!



CONCEPTUAL DESIGN



436

Nuclear Instruments and Methods in Physics Research A278 (1989) 436–440
North-Holland, Amsterdam

VLSI STRUCTURES FOR TRACK FINDING

Mauro DELL'ORSO

Dipartimento di Fisica, Università di Pisa, Piazza Torricelli 2, 56100 Pisa, Italy

Luciano RISTORI

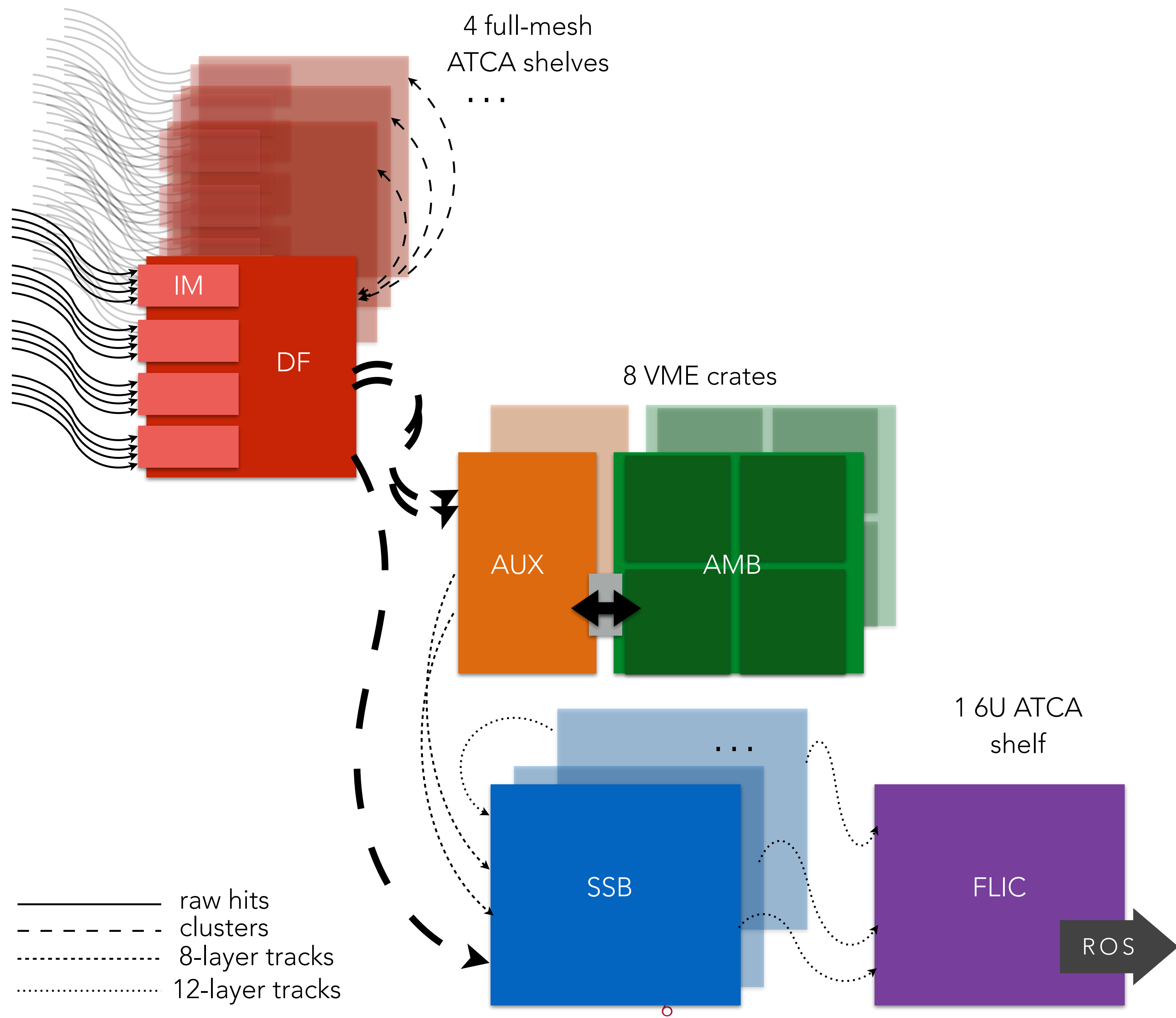
INFN Sezione di Pisa, Via Vecchia Livornese 582a, 56010 S. Piero a Grado (PI), Italy

Received 24 October 1988

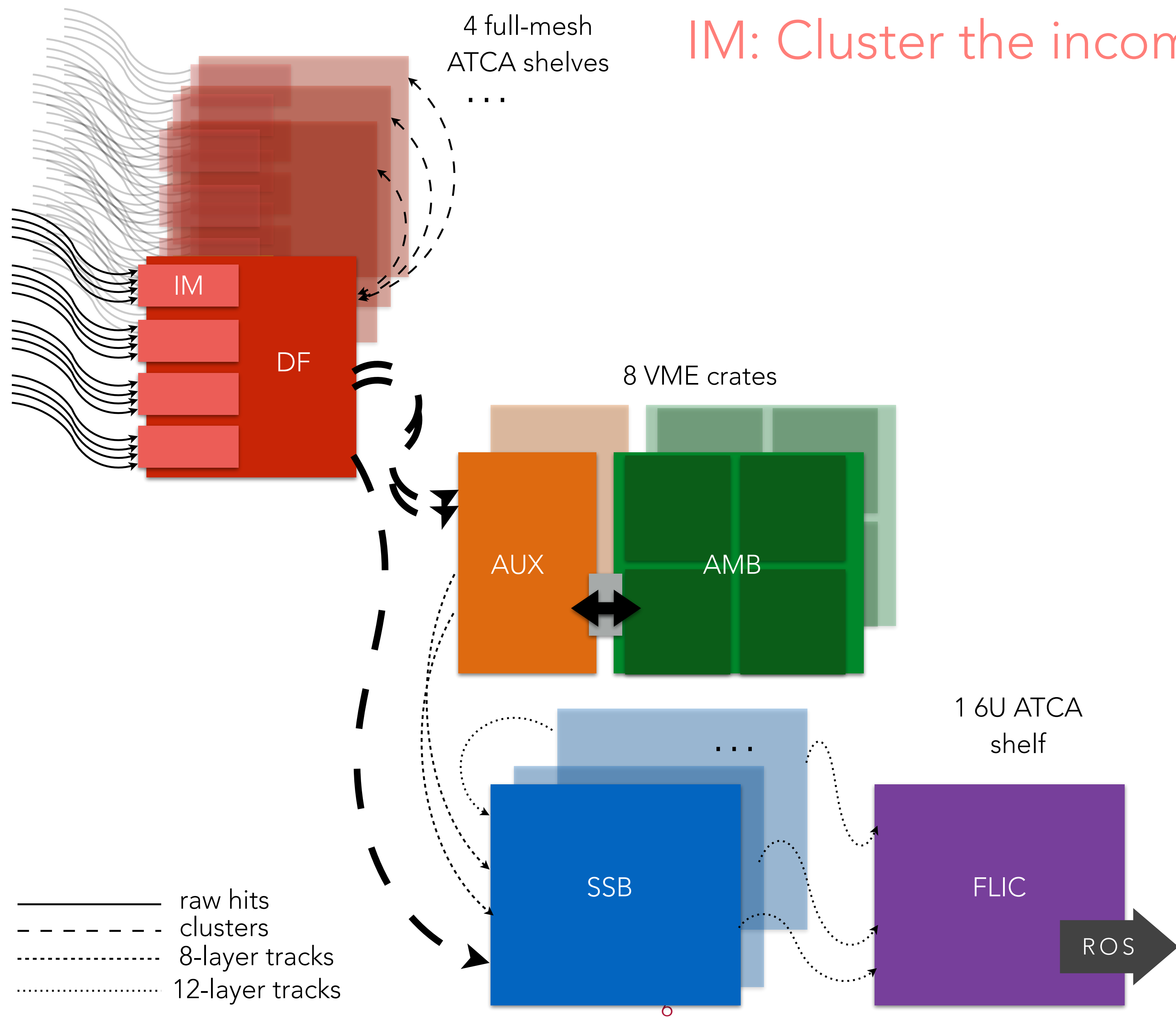
We discuss the architecture of a device based on the concept of *associative memory* designed to solve the track finding problem, typical of high energy physics experiments, in a time span of a few microseconds even for very high multiplicity events. This "machine" is implemented as a large array of custom VLSI chips. All the chips are equal and each of them stores a number of "patterns". All the patterns in all the chips are compared in parallel to the data coming from the detector while the detector is being read out.

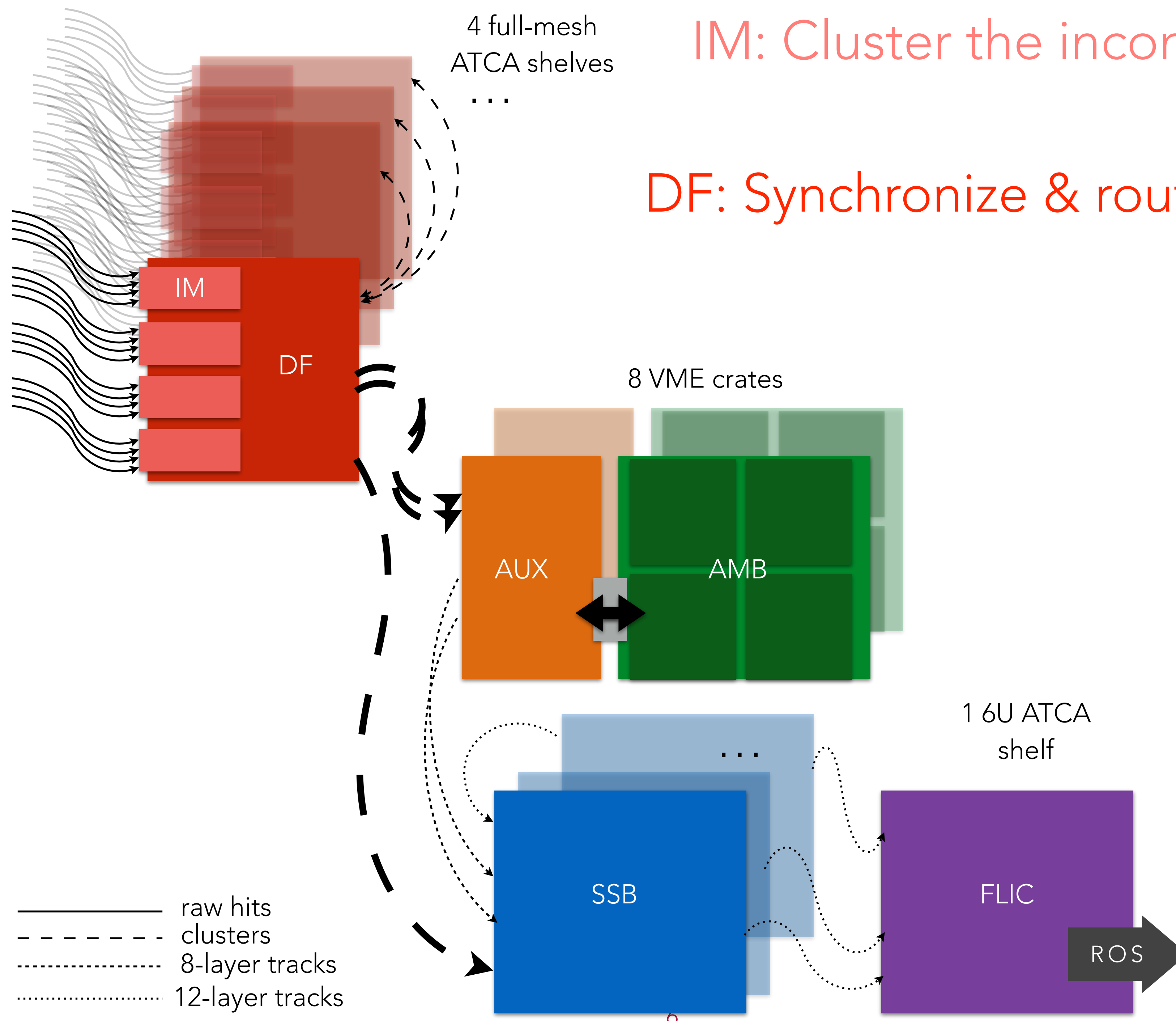
- **Parallelize** the problem: Divide the detector η - ϕ towers
- **Reduce** the data volume: Convert clusters into coarse resolution hits
- **Eliminate** costly loops: Compare hits to pre-stored patterns simultaneously
- **Simplify** algorithms: Use a linearized fit for track candidates
- **Hardware** solution: Implemented in FPGAs or custom ASICs





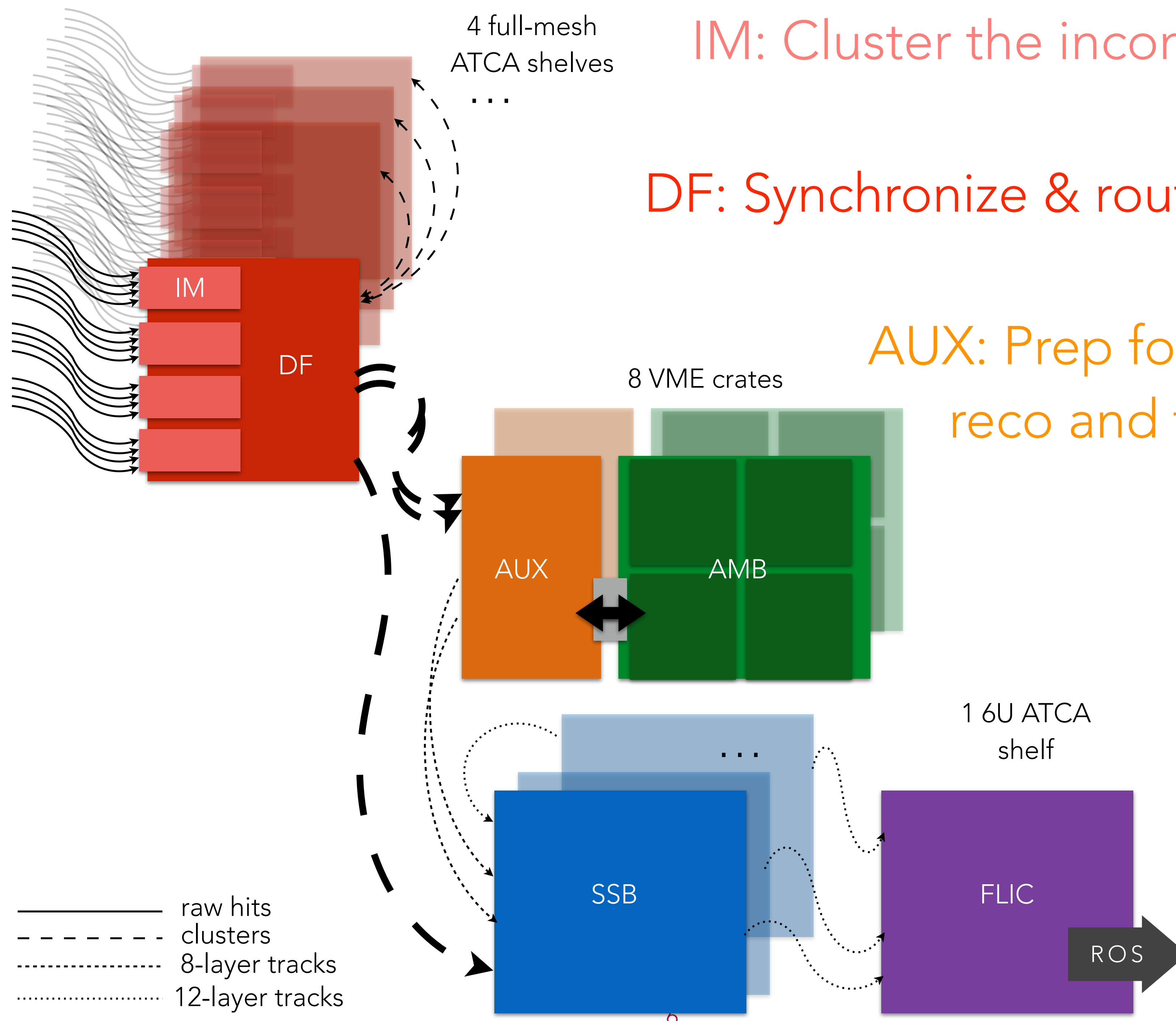
IM: Cluster the incoming data (128)





IM: Cluster the incoming data (128)

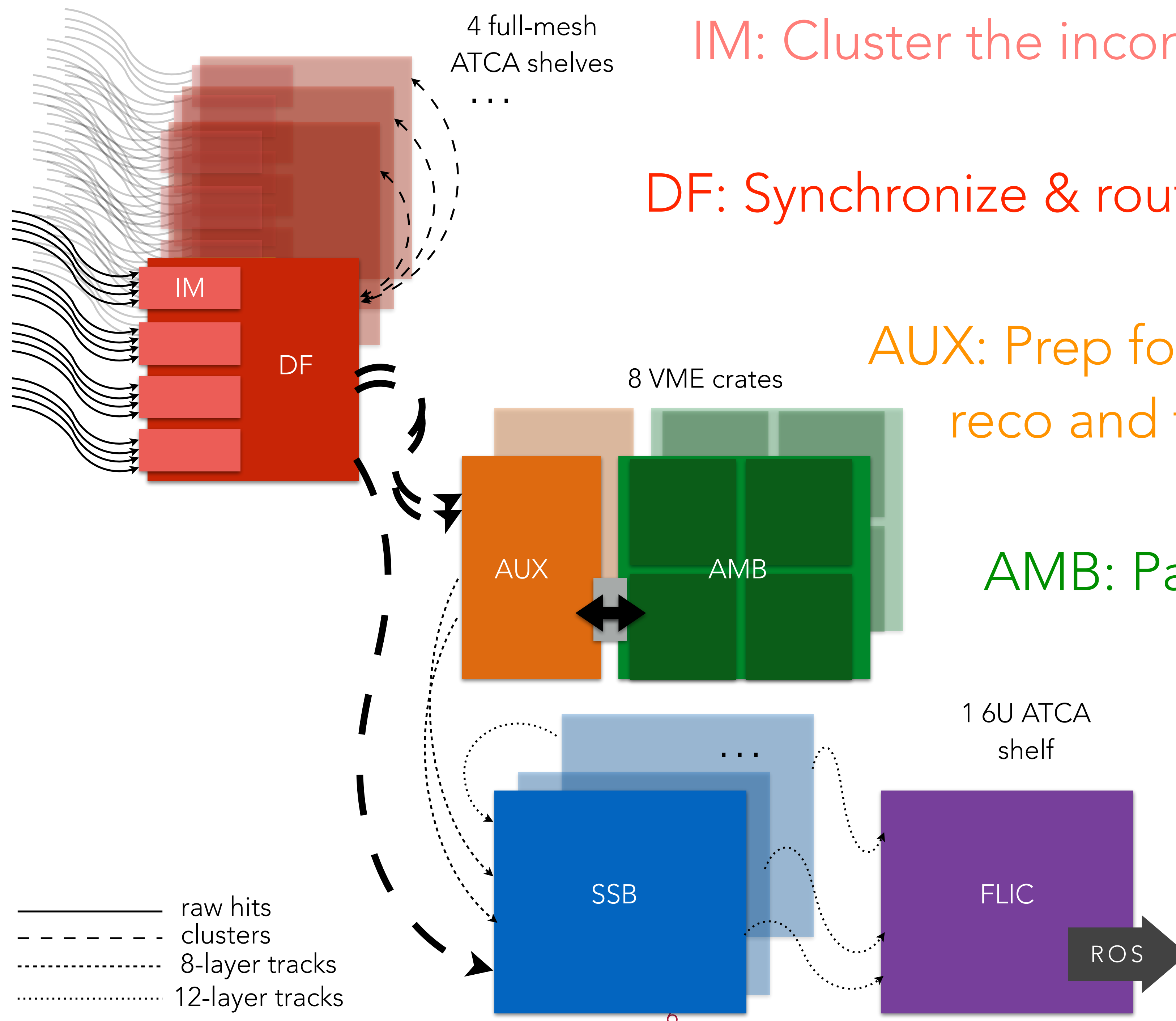
DF: Synchronize & route to towers (32)



IM: Cluster the incoming data (128)

DF: Synchronize & route to towers (32)

AUX: Prep for 8-layer pattern reco and track fit (128)

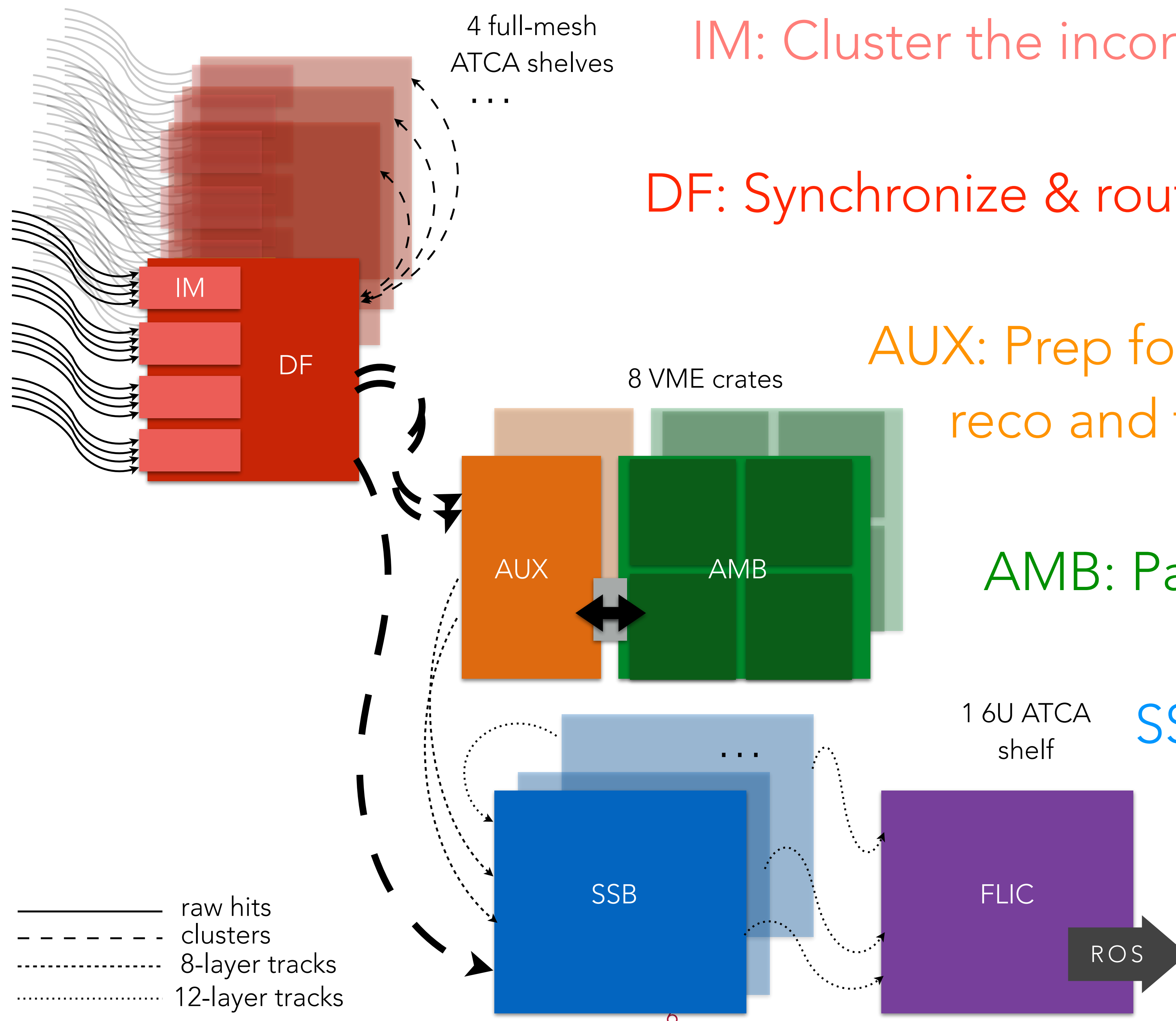


IM: Cluster the incoming data (128)

DF: Synchronize & route to towers (32)

AUX: Prep for 8-layer pattern reco and track fit (128)

AMB: Pattern reco (128)



IM: Cluster the incoming data (128)

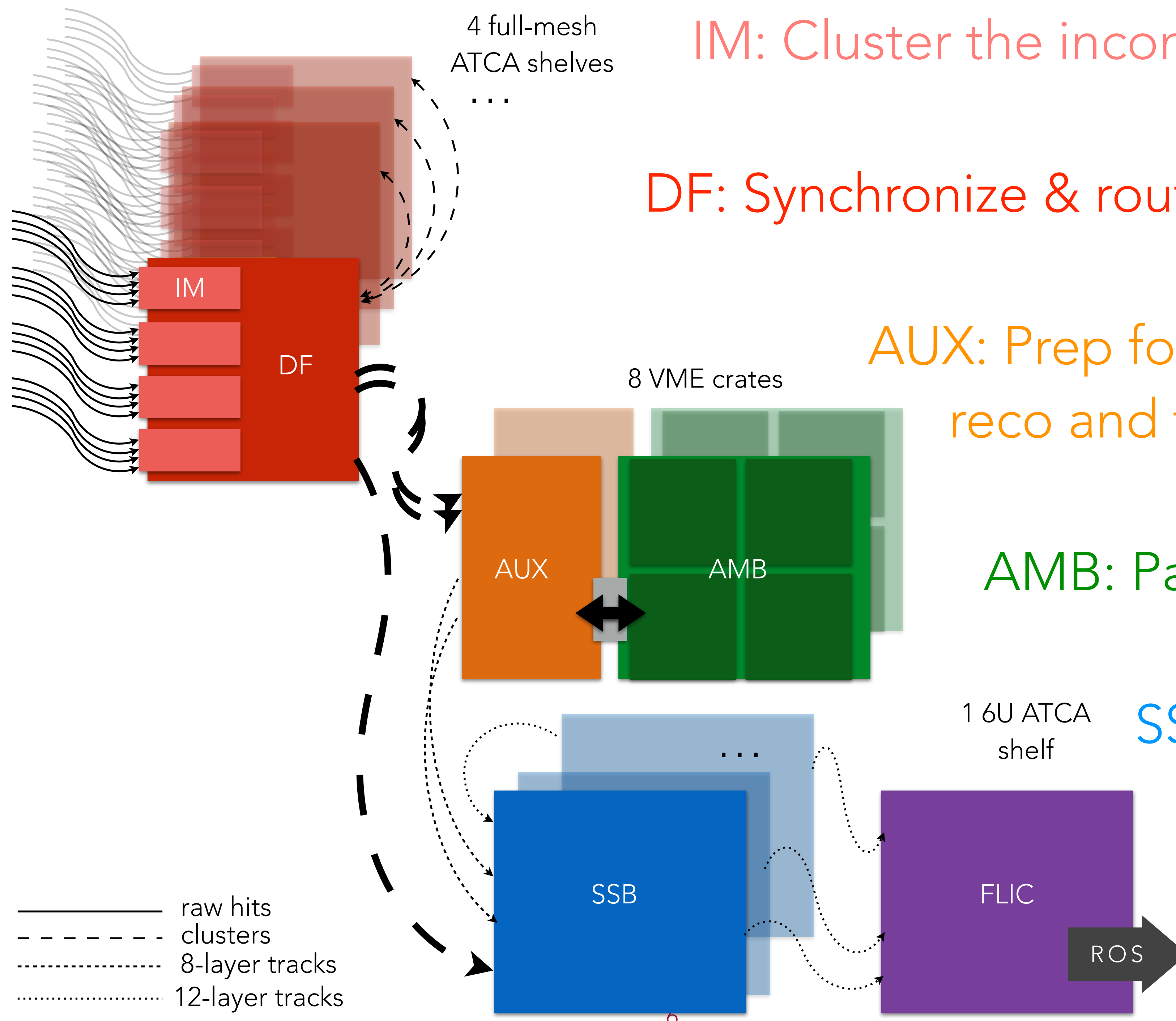
DF: Synchronize & route to towers (32)

AUX: Prep for 8-layer pattern reco and track fit (128)

AMB: Pattern reco (128)

SSB: 12-layer fit (32)

- raw hits
- - - clusters
- 8-layer tracks
- 12-layer tracks



IM: Cluster the incoming data (128)

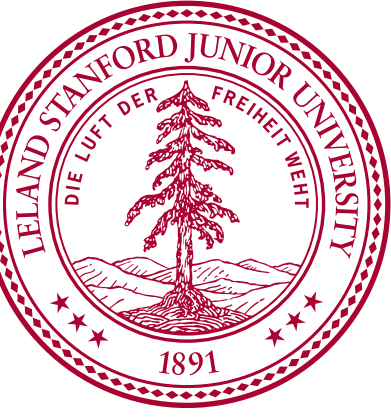
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AUX: Prep for 8-layer pattern reco and track fit (128)

AMB: Pattern reco (128)

SSB: 12-layer fit (32)

FLIC: Format for HLT (2)

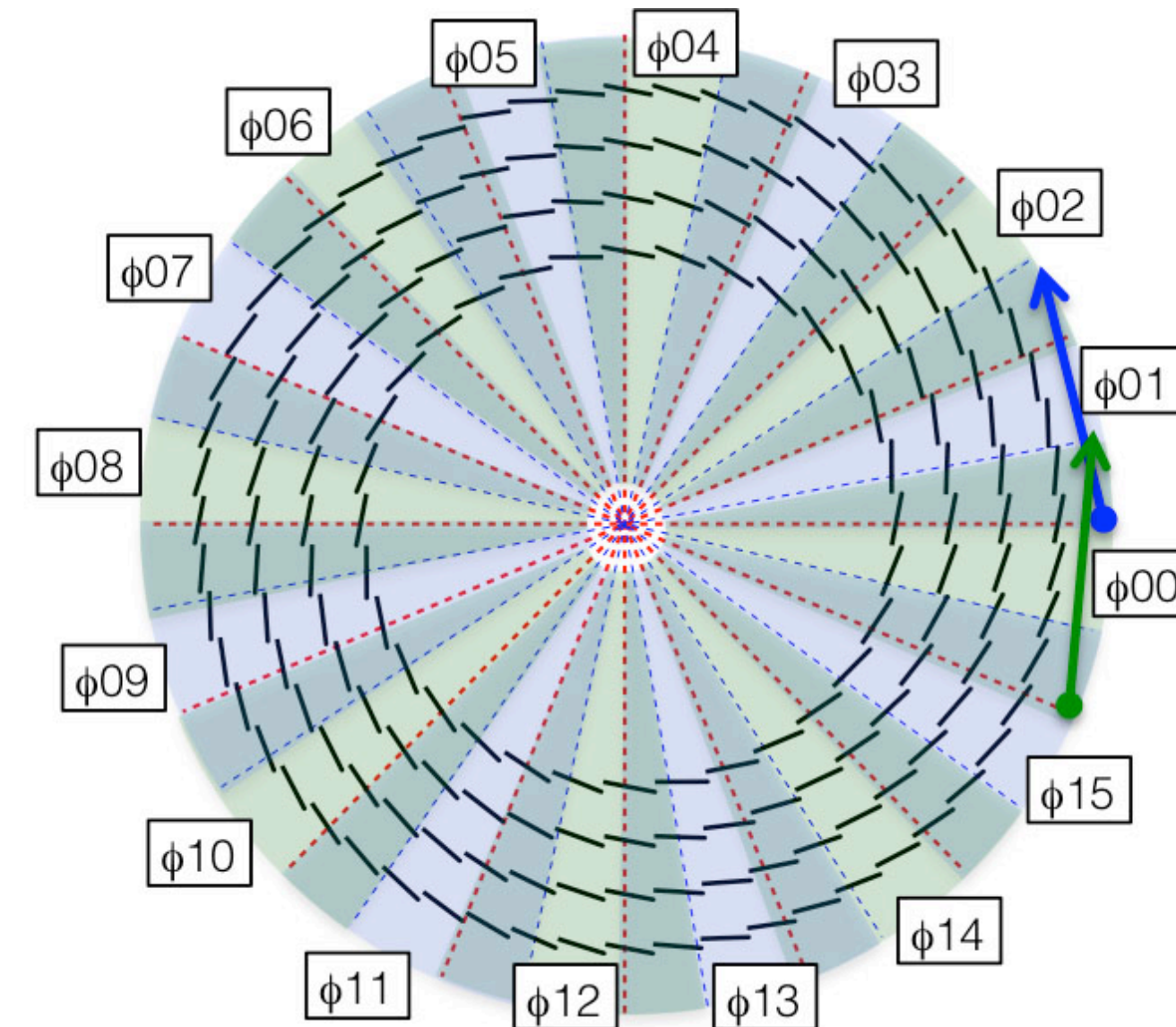
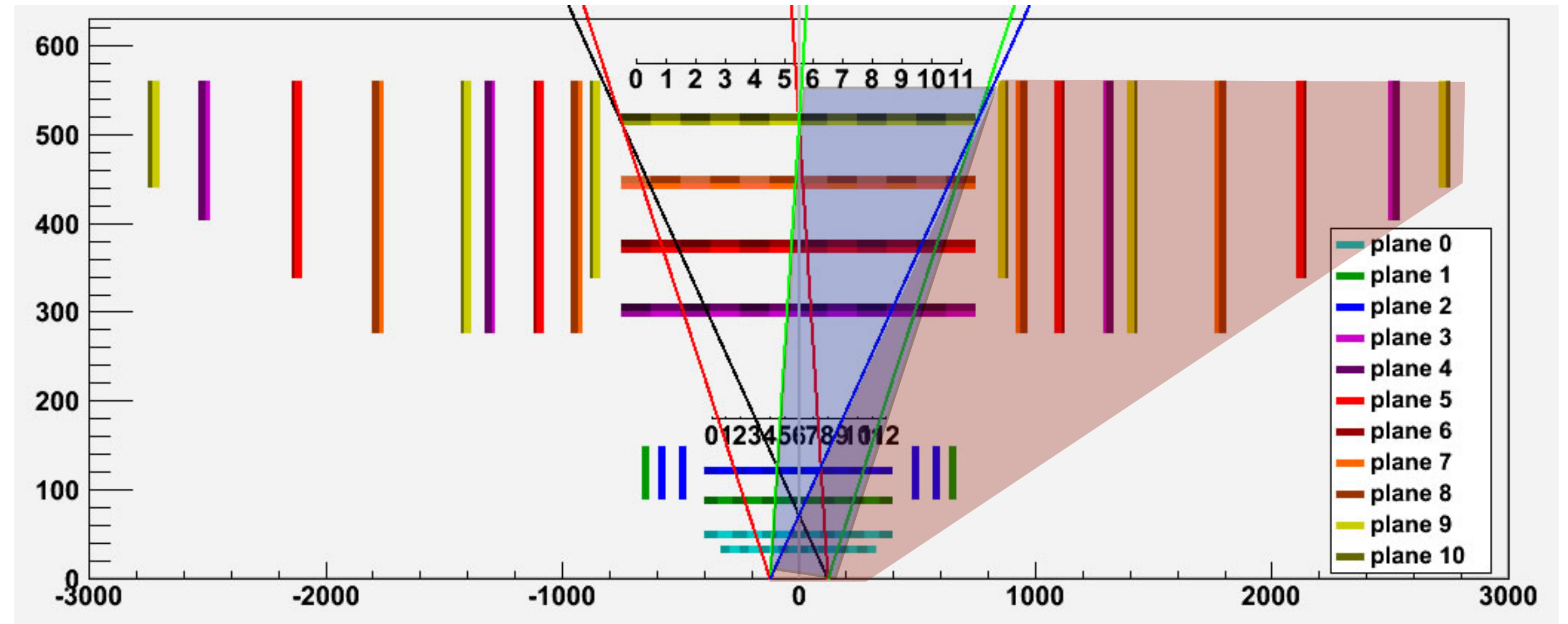


STAGE 1: DATA FORMATTING

- Cluster hits (sliding window algorithm on Spartan 6 and Artix 7 FPGAS)
- Synchronize events
 - Majority logic on input and output
- Route clusters to FTK eta-phi towers
 - High overlap fraction of towers
 - Implemented in Banyan switches

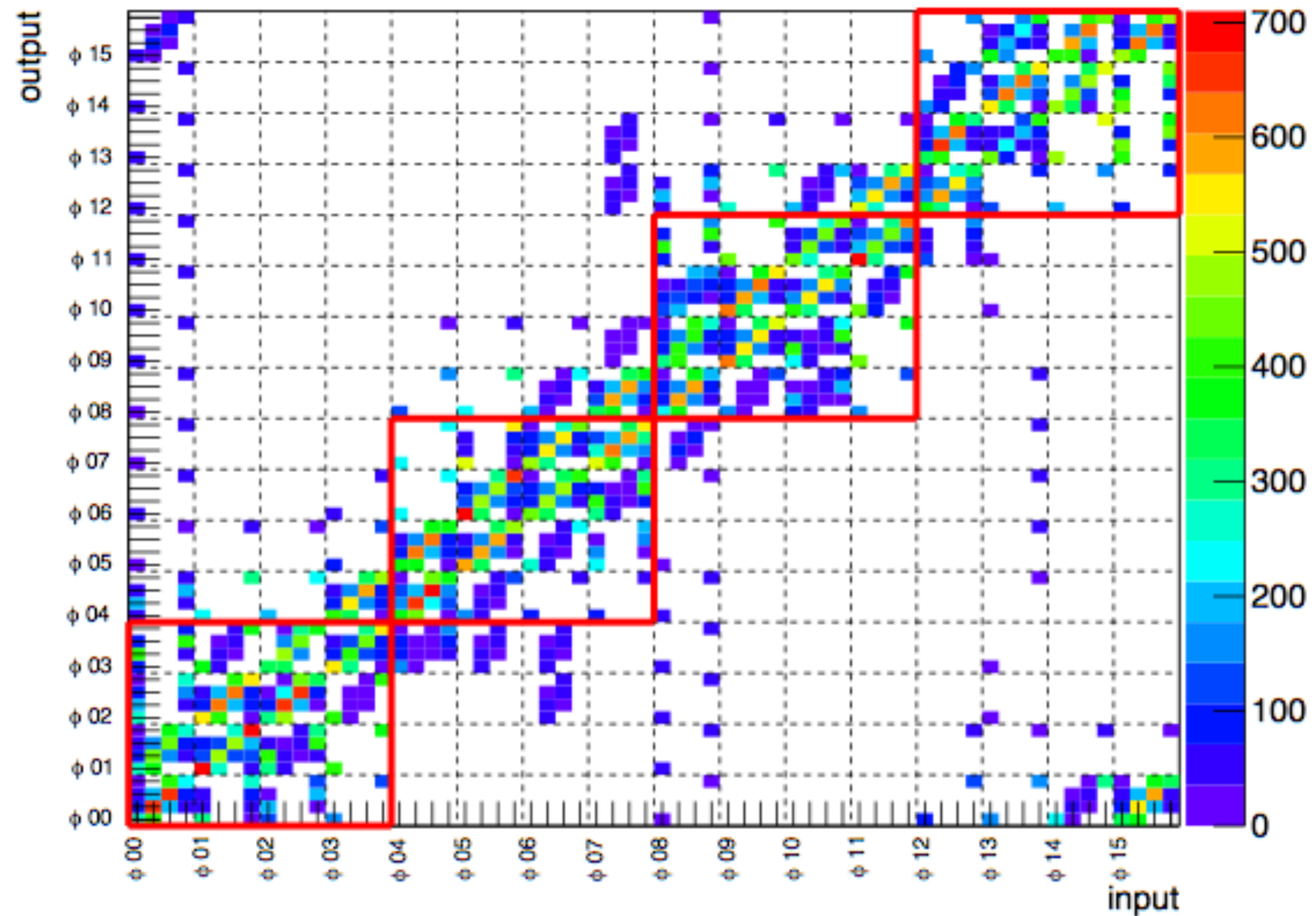
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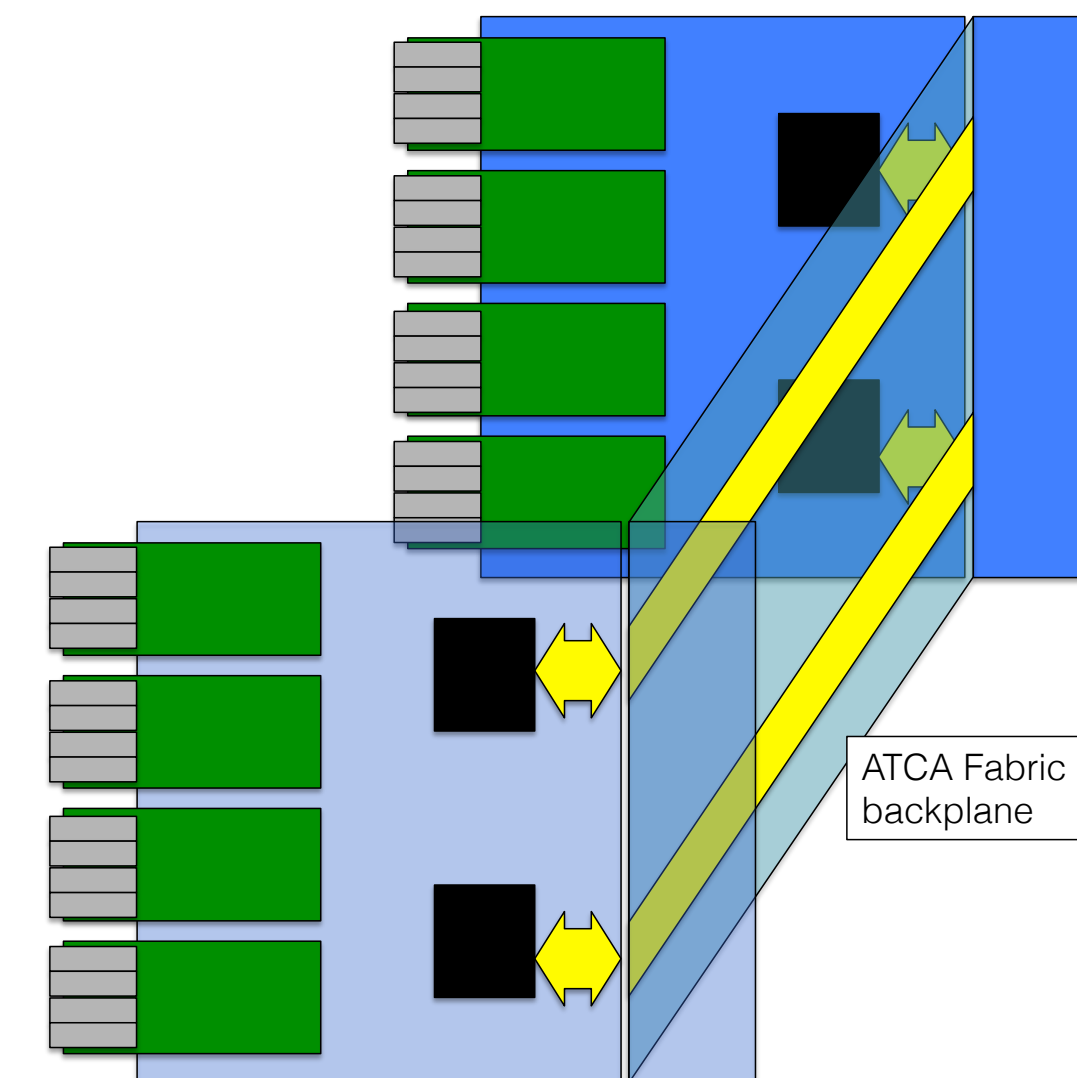
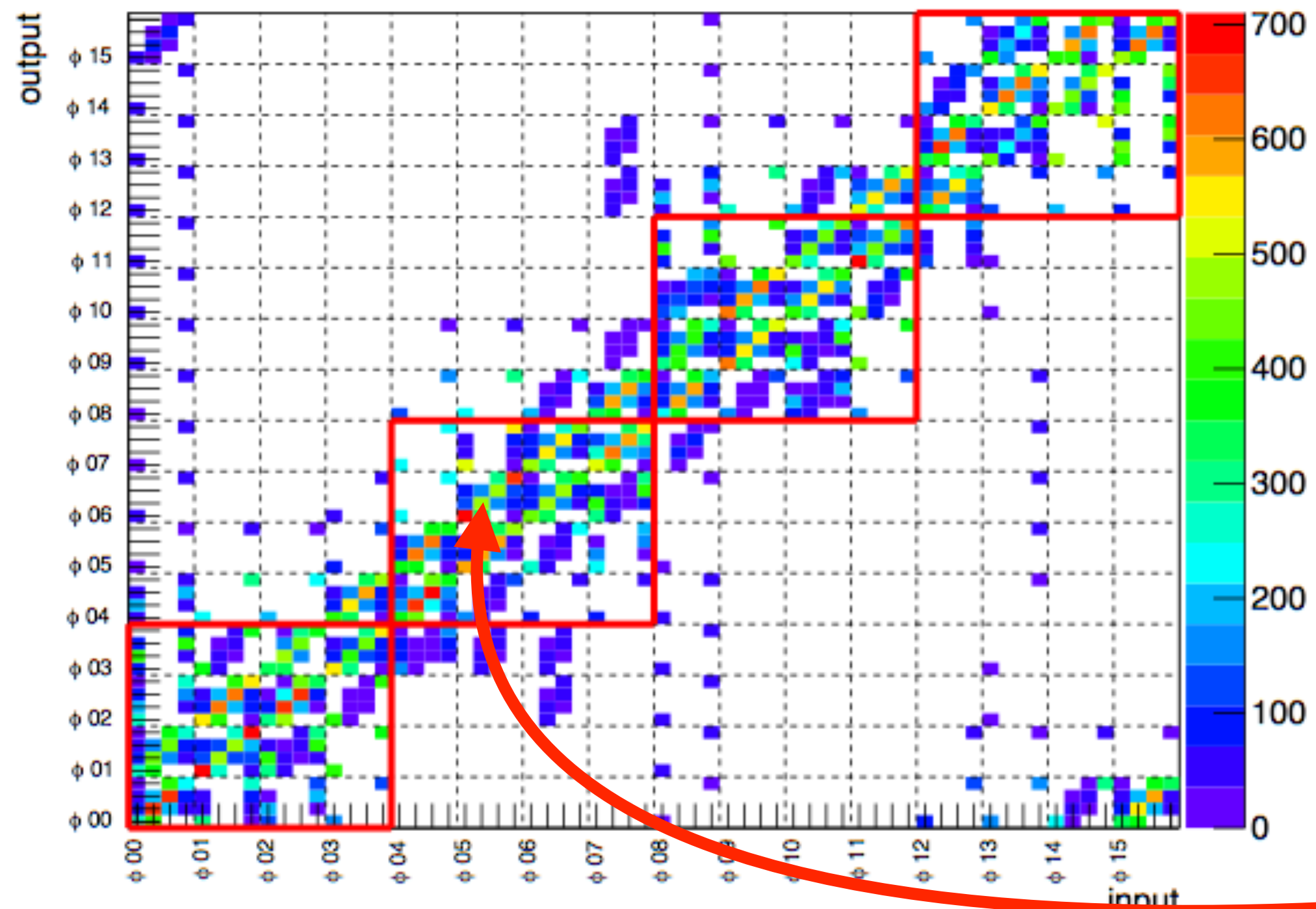
STAGE 1: DATA FORMATTING

- Implemented in 32 boards in 4 ATCA crates with full mesh backplane (40Gbps), Virtex 7 FPGA on each board
- Data aggregation challenges:
 - Silicon detector readout not projective!
 - System had no L1 decision info as input — had to decode from input data



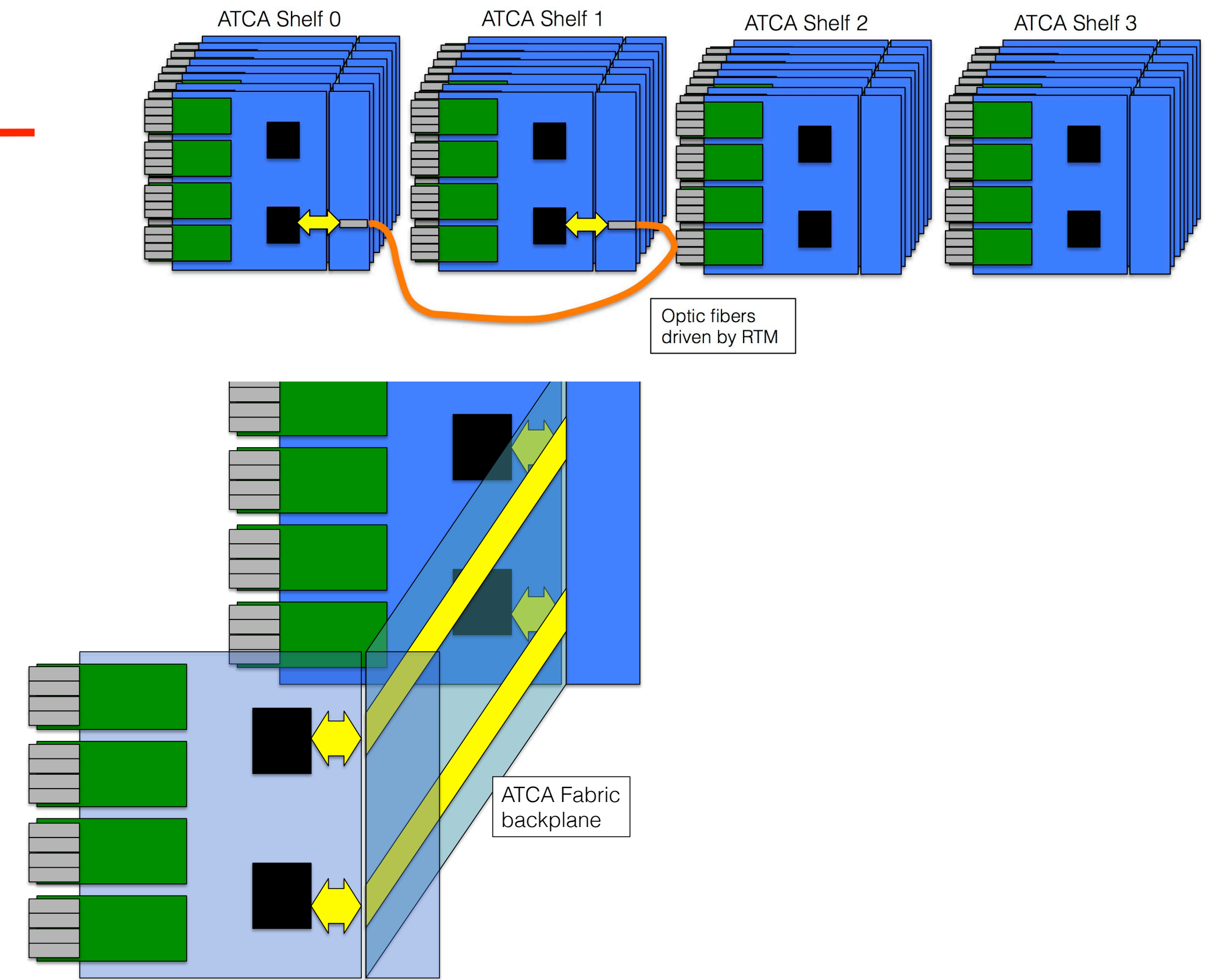
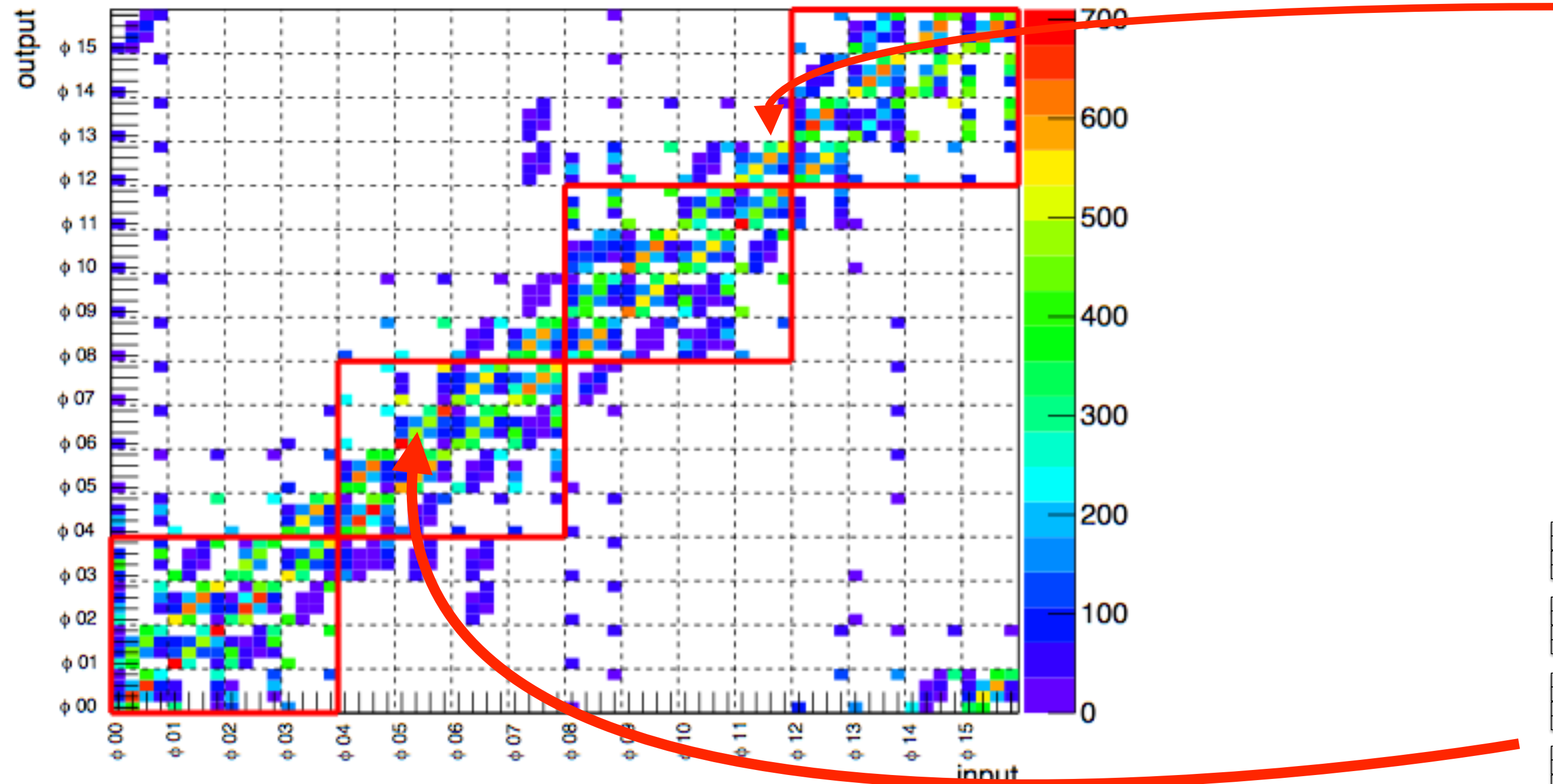
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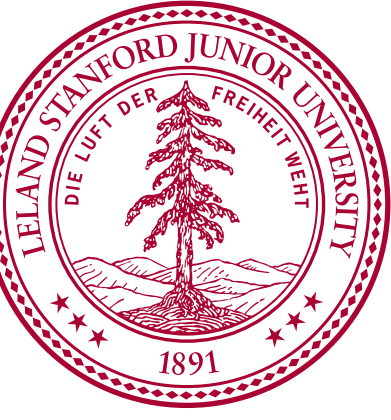
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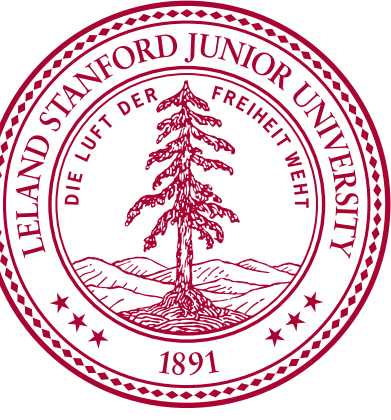




STAGE 2: BINGO

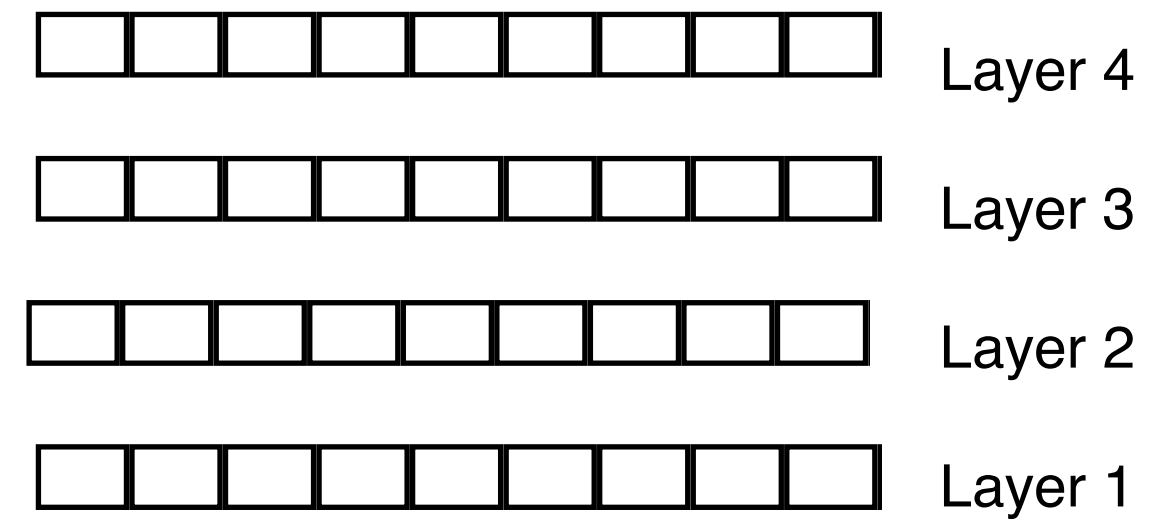
DATA REDUCTION AND PATTERN RECOGNITION

- Hits are ganged together into coarse resolution hits

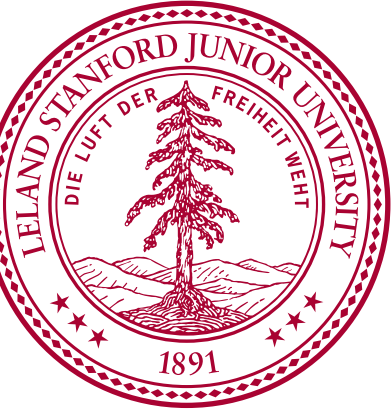


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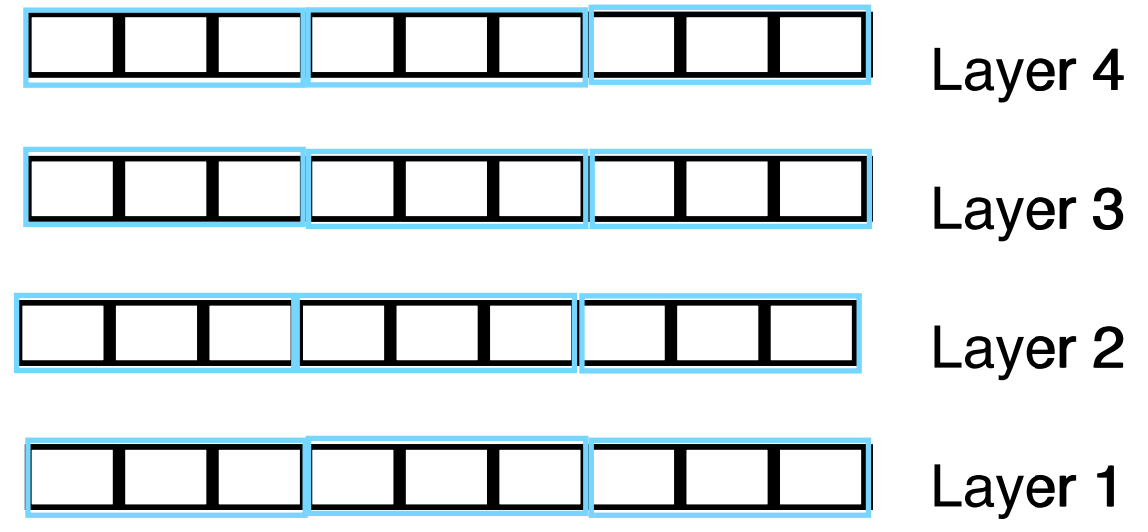


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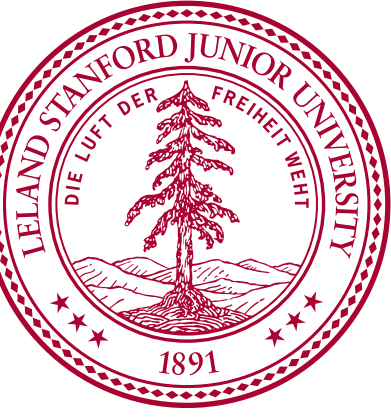


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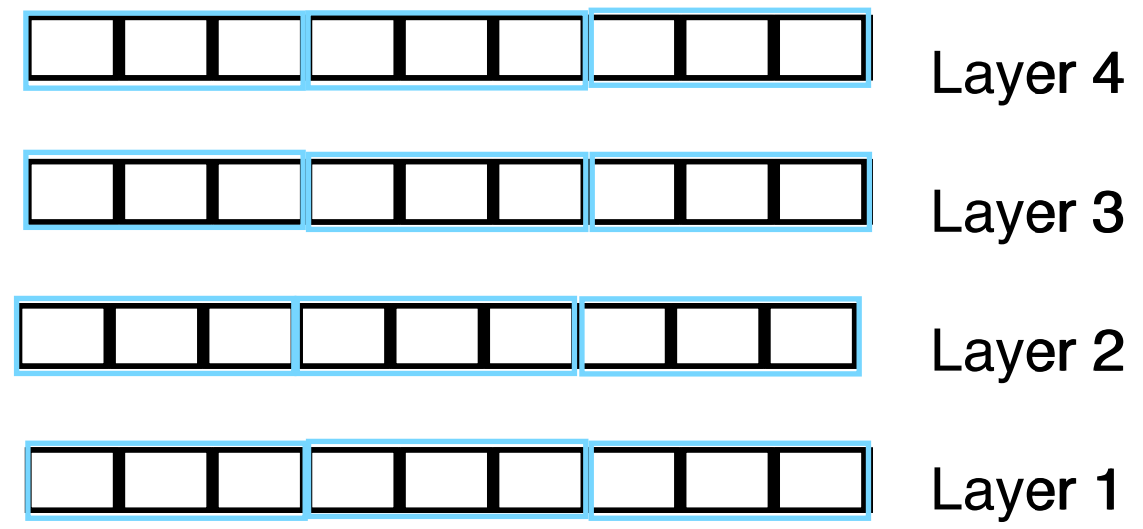


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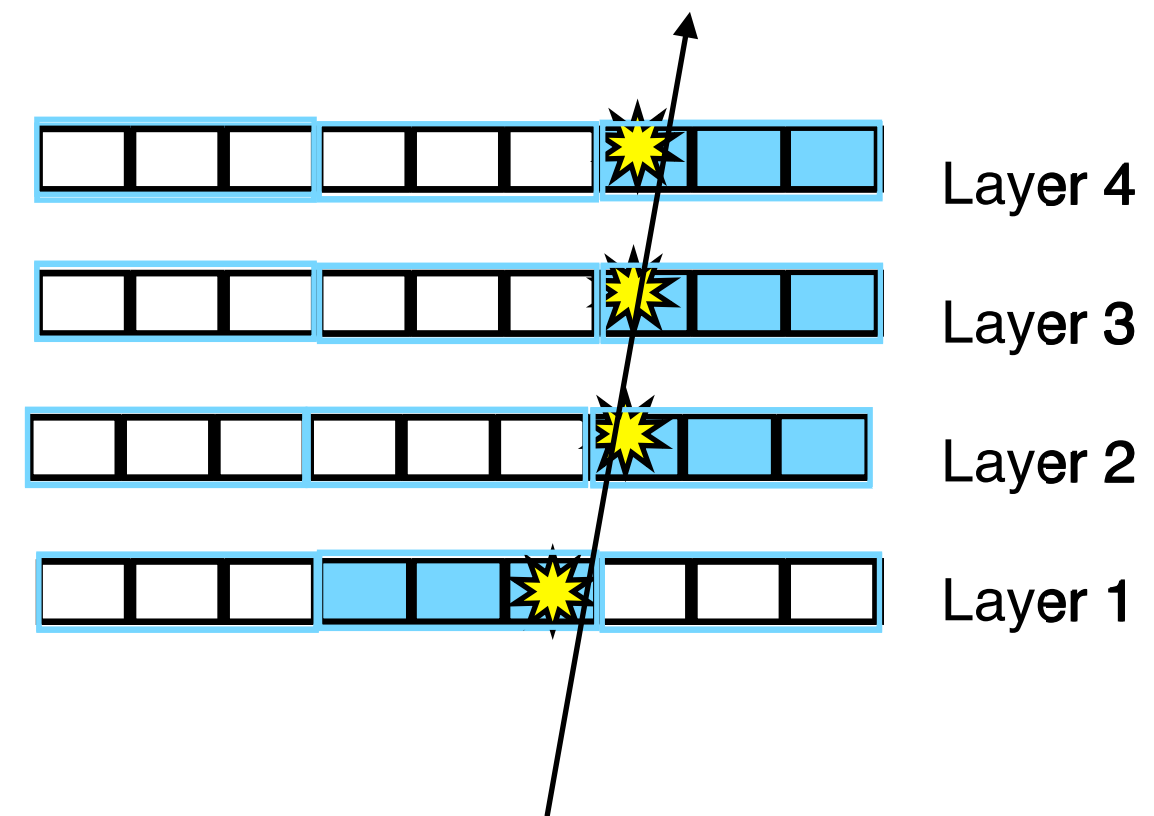


- Hits are ganged together into coarse resolution hits

- All possible patterns of coarse resolution hits determined from simulation

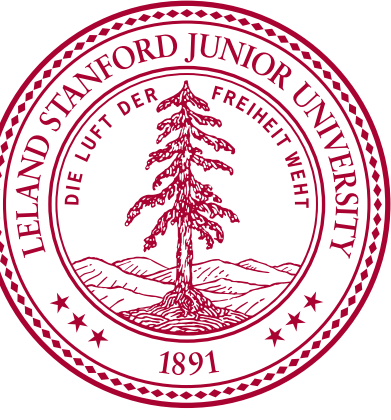
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DATA REDUCTION AND PATTERN RECOGNITION



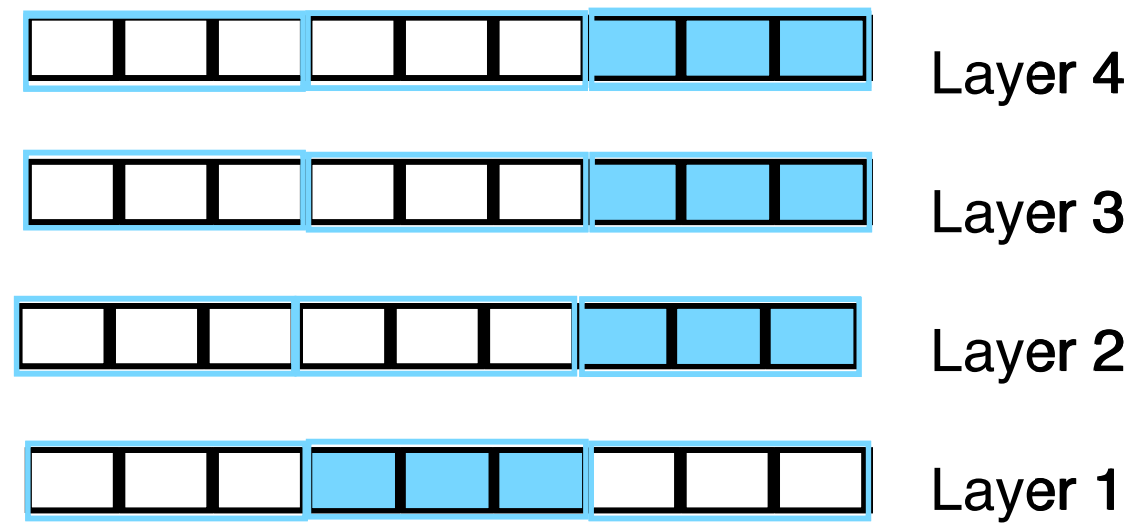
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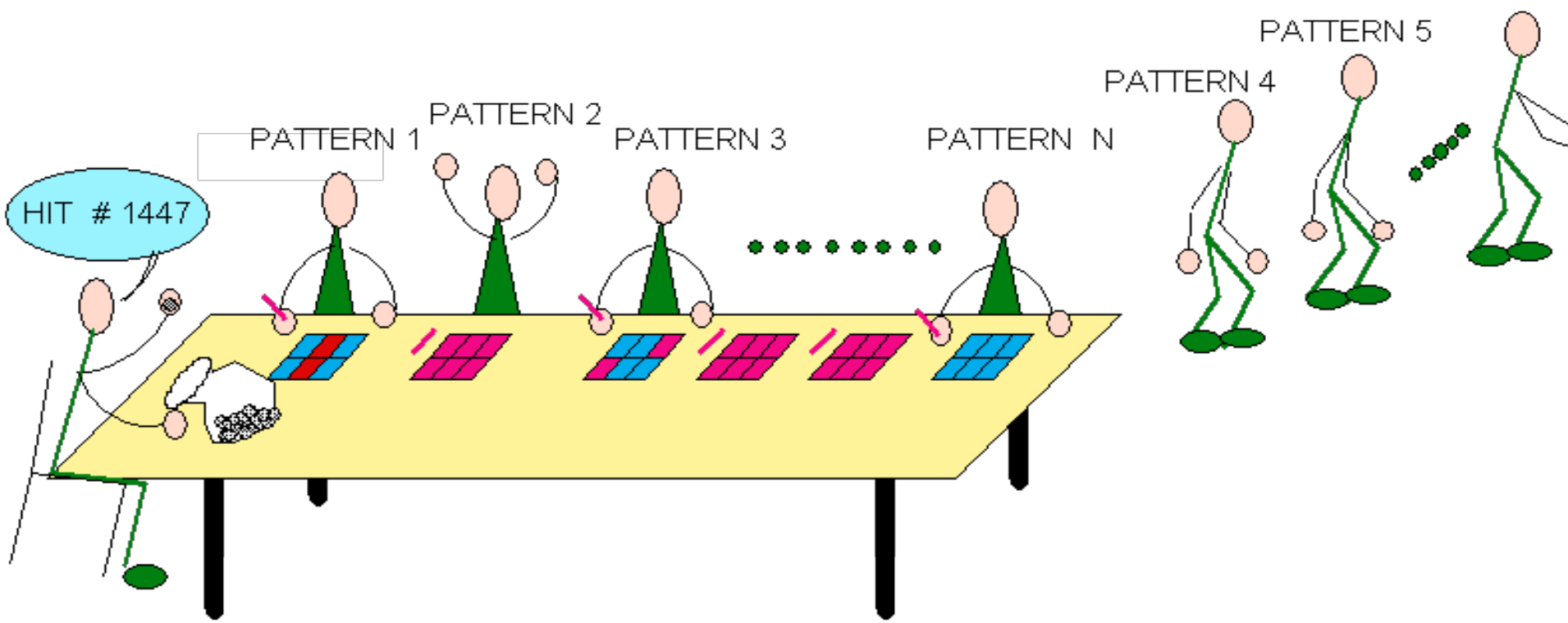
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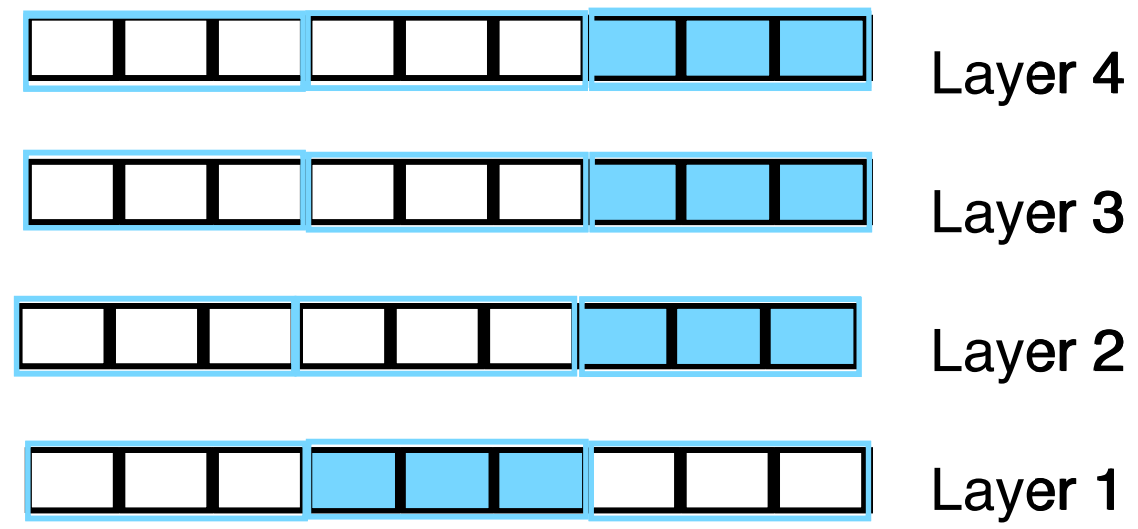
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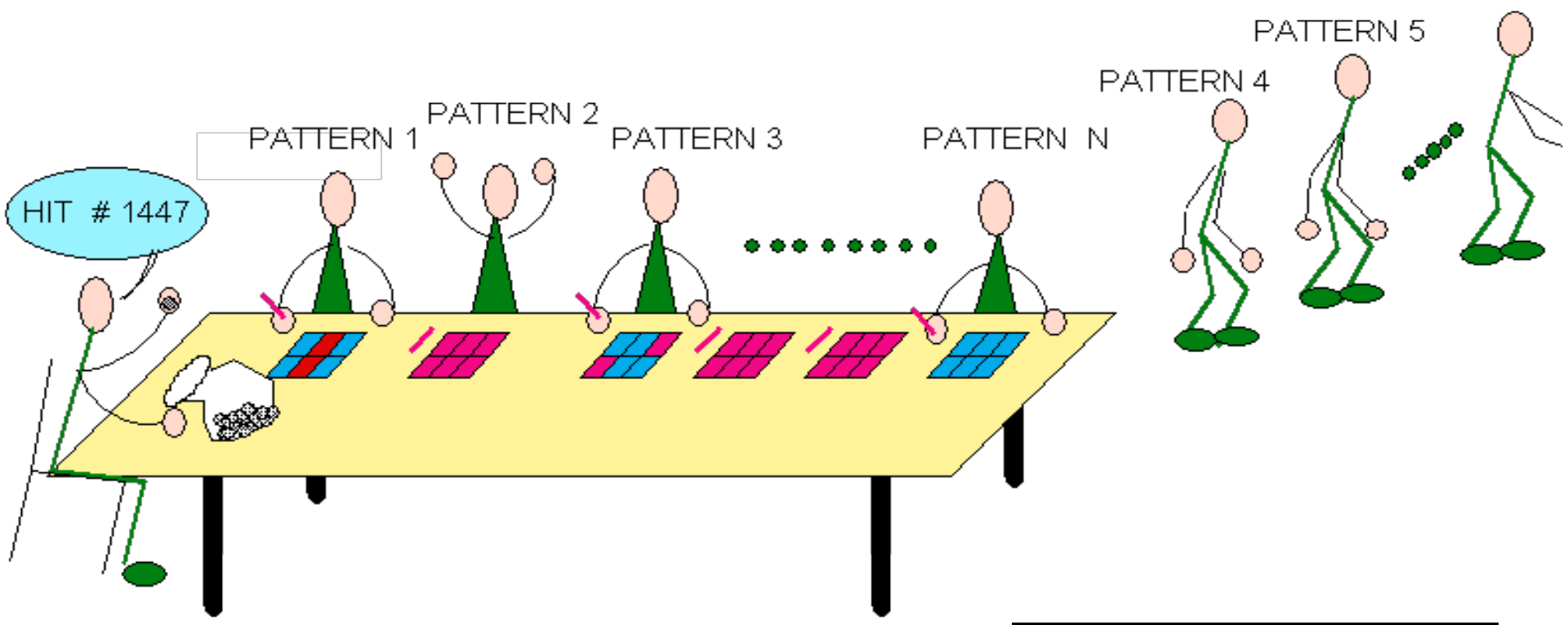
- All possible patterns of coarse resolution hits determined from simulation
- Custom associative memory chips are used to **compare hits** to $O(10^9)$ patterns **simultaneously** (bingo cards)

STAGE 2: BINGO

DATA REDUCTION AND PATTERN RECOGNITION

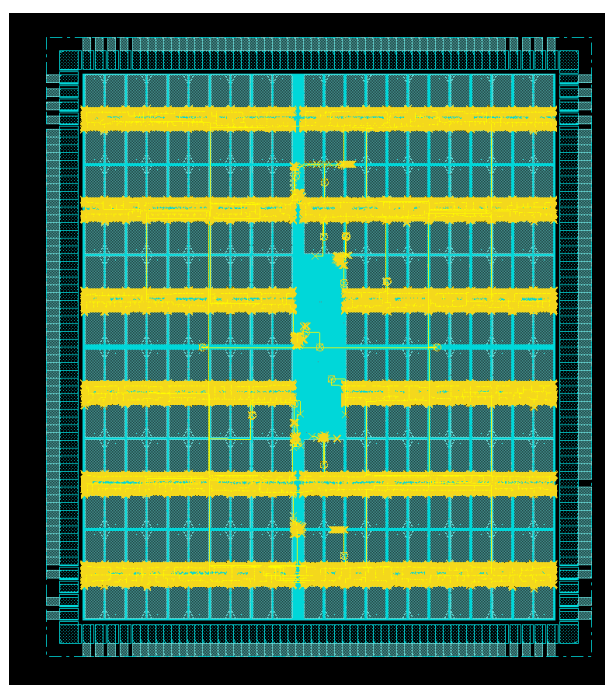


- Hits are ganged together into coarse resolution hits



- All possible patterns of coarse resolution hits determined from simulation

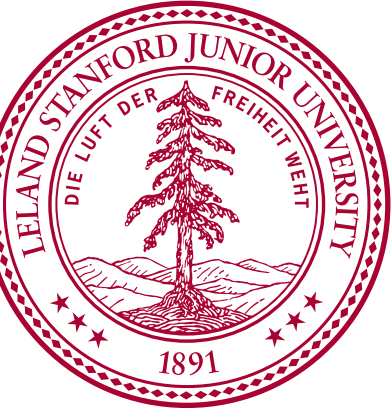
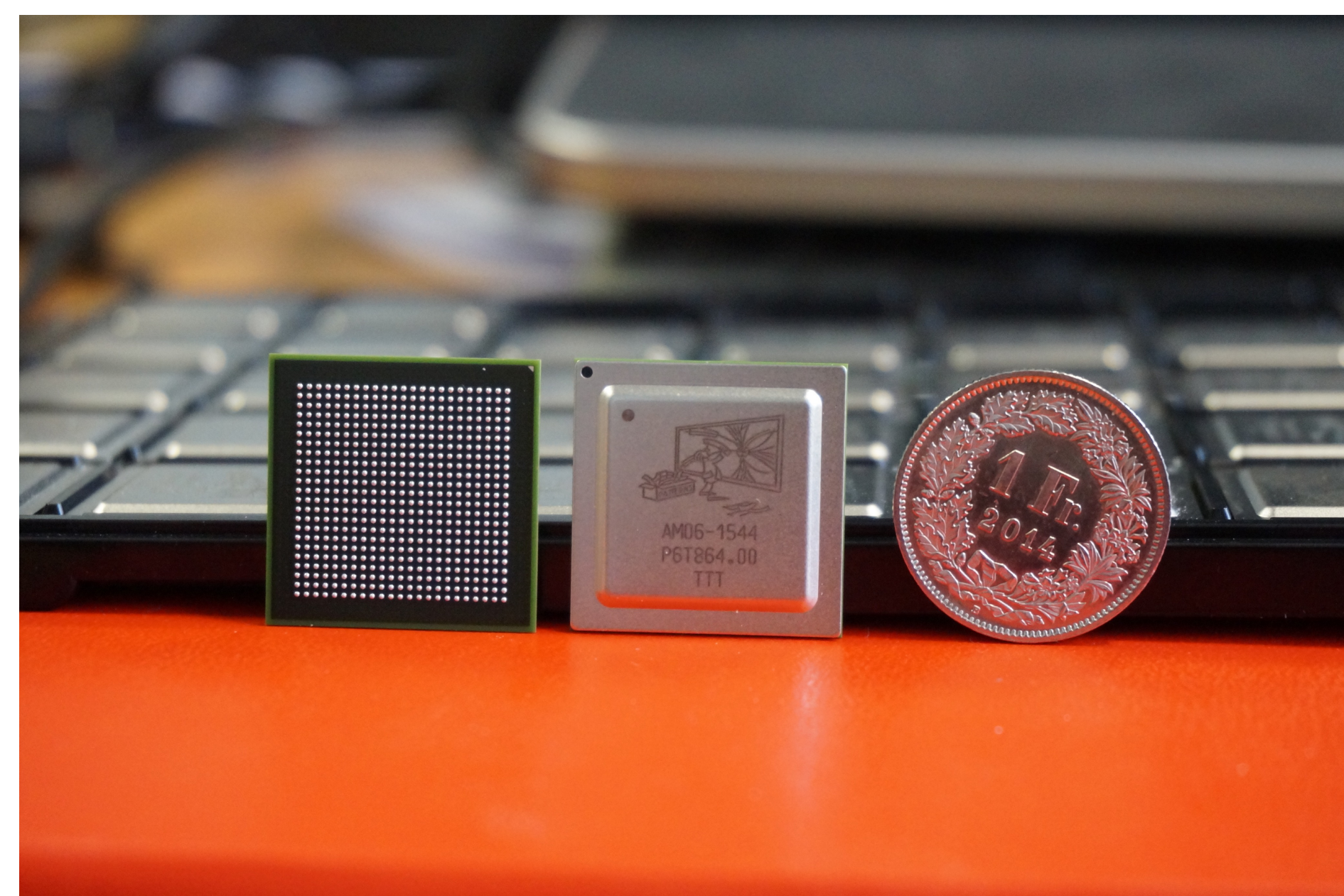
AMChip06



- Custom associative memory chips are used to **compare hits** to $O(10^9)$ patterns **simultaneously** (bingo cards)

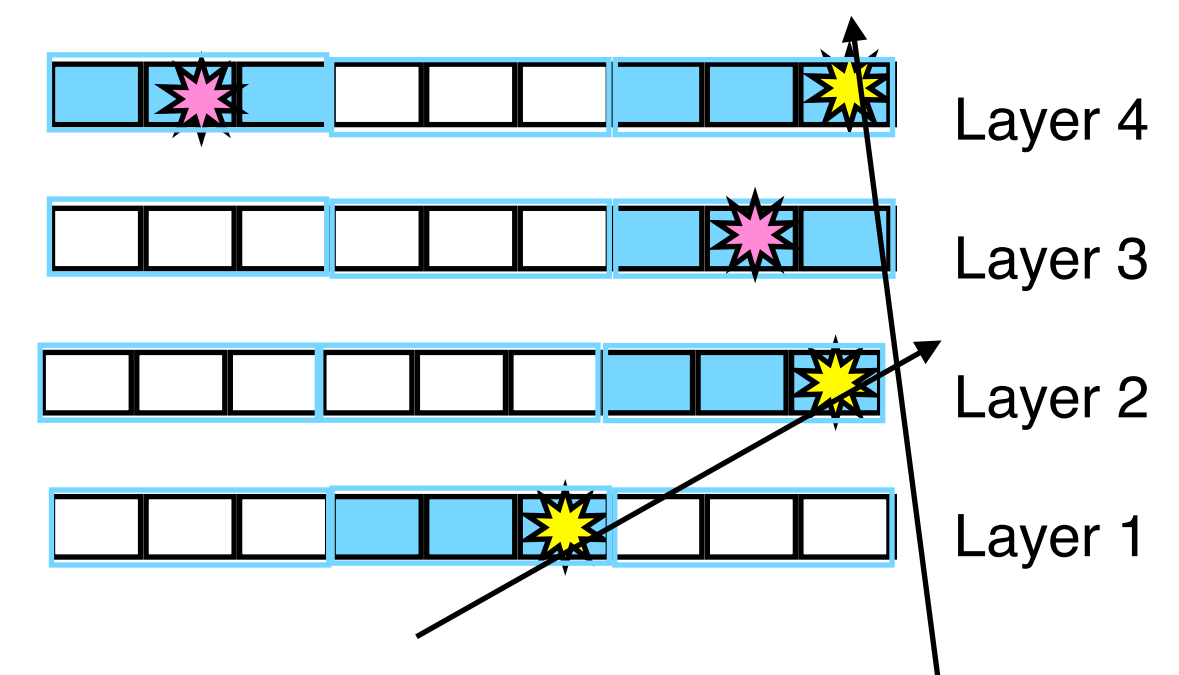
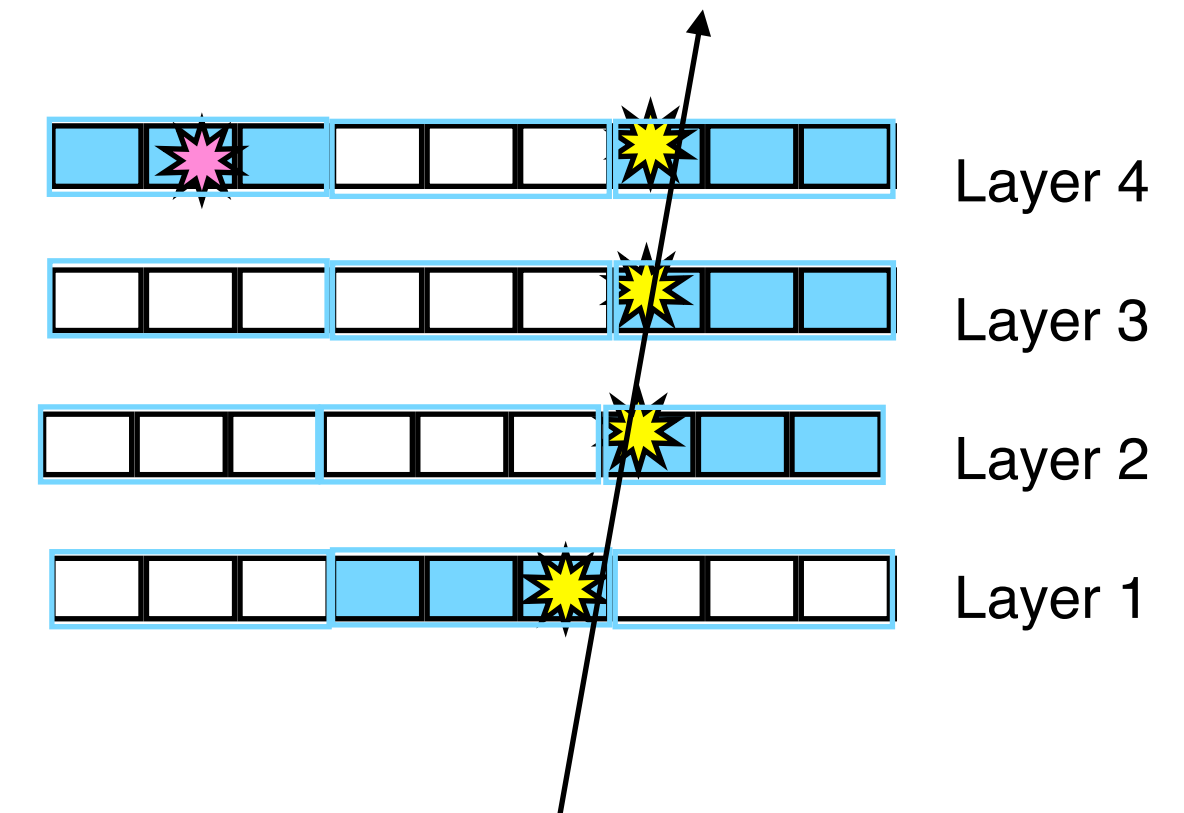
AMCHIP 06 VITAL STATS

- 65 nm fabrication
- 60mm² area
- 2 Gb/s I/O
- 23x23 BGA
- 128k patterns, 400M transistors
- 1.15V, 3.3 A, 3.8 W / chip
- ~ 85% production yield



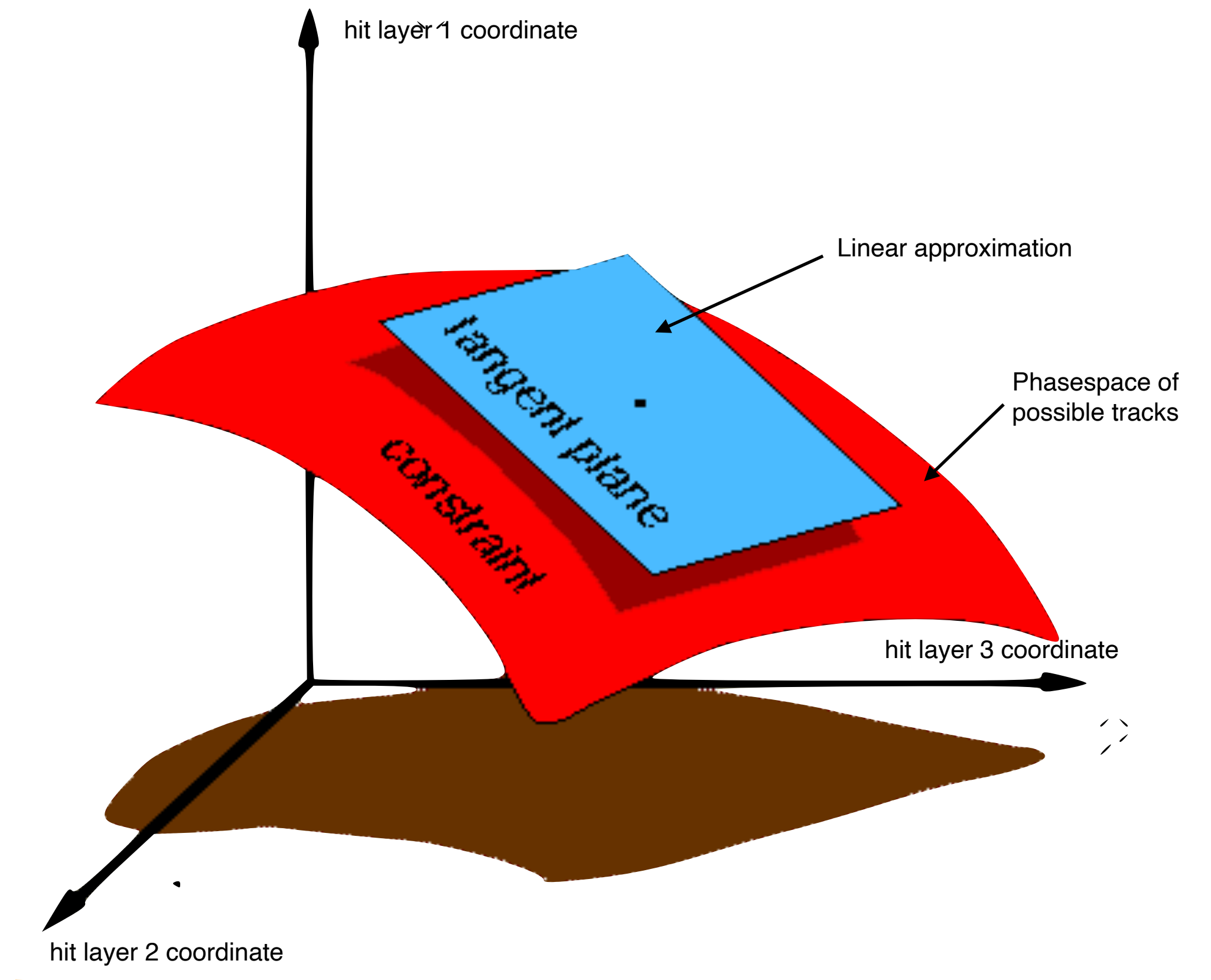
TRACK FITTING

- Problem: $>90\%$ of matched patterns (BINGOs) are from random association of hits
- Solution: check if **full resolution** hits in matched patterns are compatible with a single charged particle



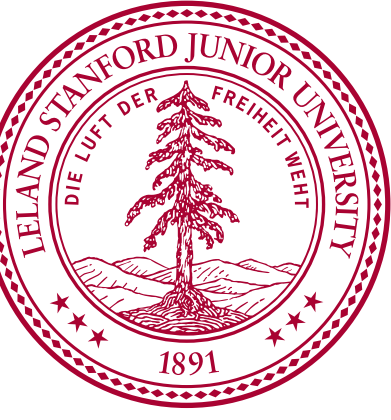
5 PICOSECOND TRACK FITTING

- Linearized fits on FPGAs:
 - Determine phasespace of possible tracks (χ^2)
 - Linear approximation calculated and defined by sector
 - FPGAs multiply and add coordinates by constants to get χ^2
- Keep roads with at least 1 good track
- Fit 1 track / ns (1 track every 5 ps for full system)!



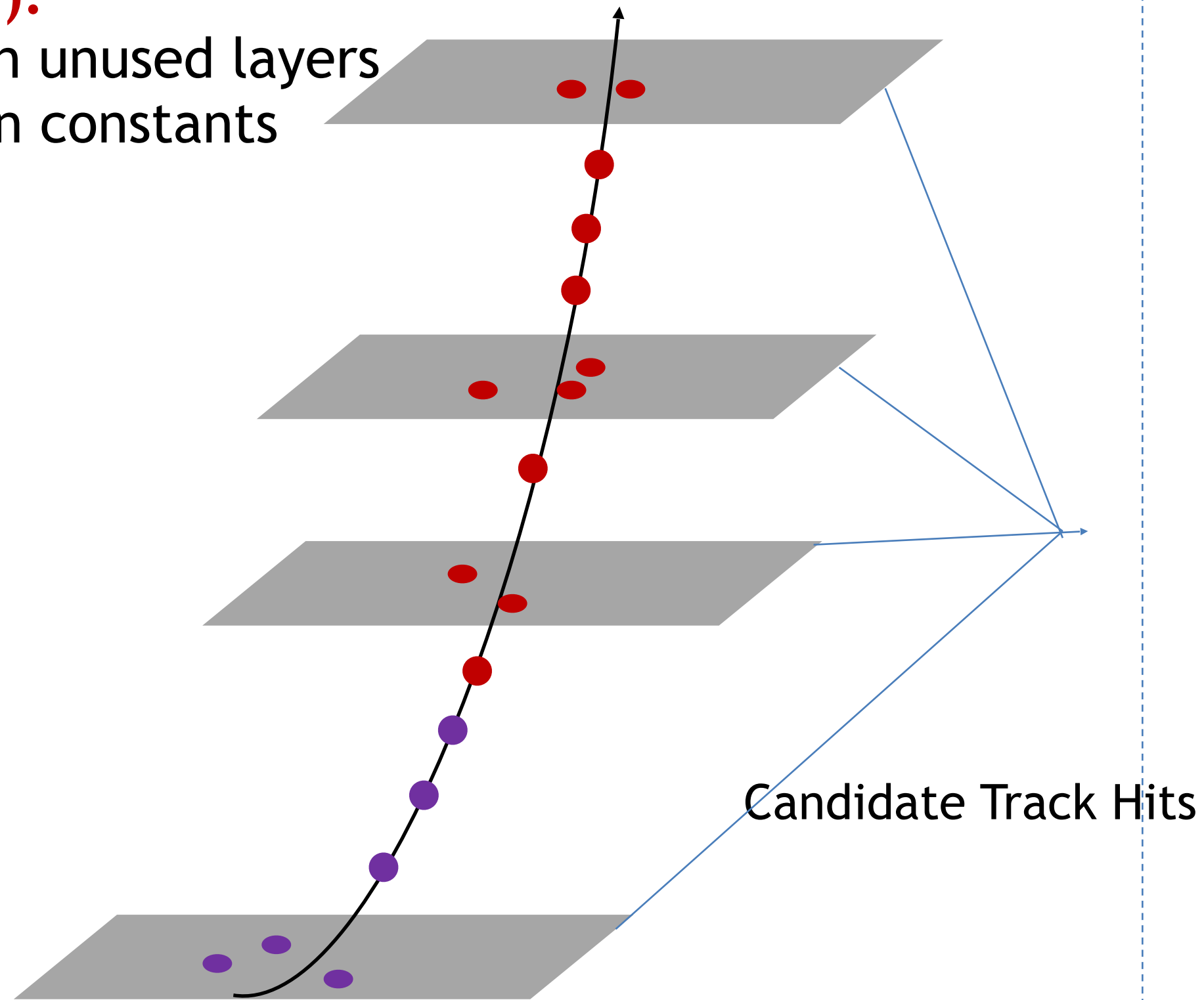
$$\chi_i = \sum_{j=1}^{N_c} S_{ij} x_j + h_i; i = 1, \dots, N_\chi$$

FINAL TRACK PRODUCTION



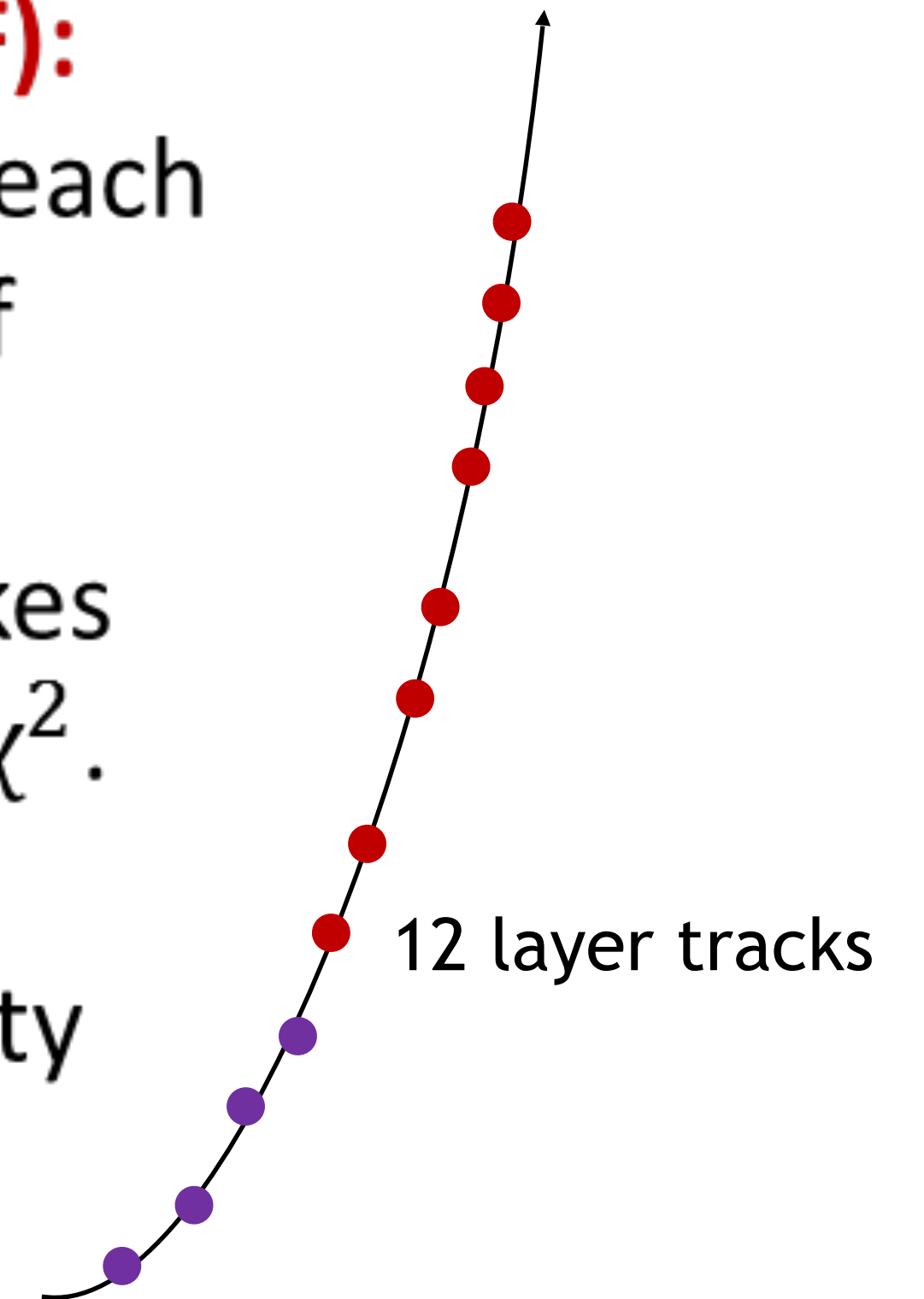
Extrapolator (EXT):

Finds candidates in unused layers using extrapolation constants

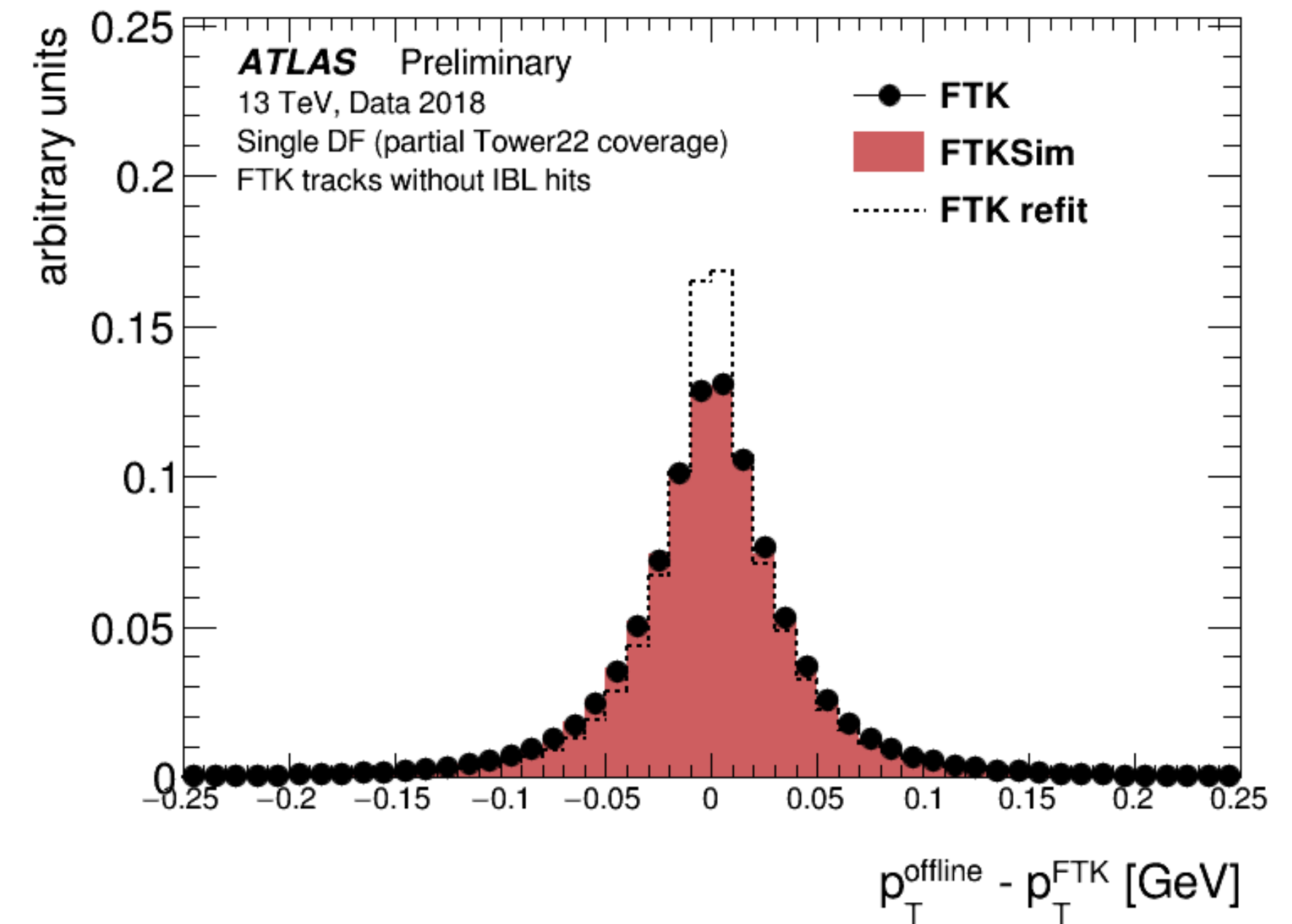
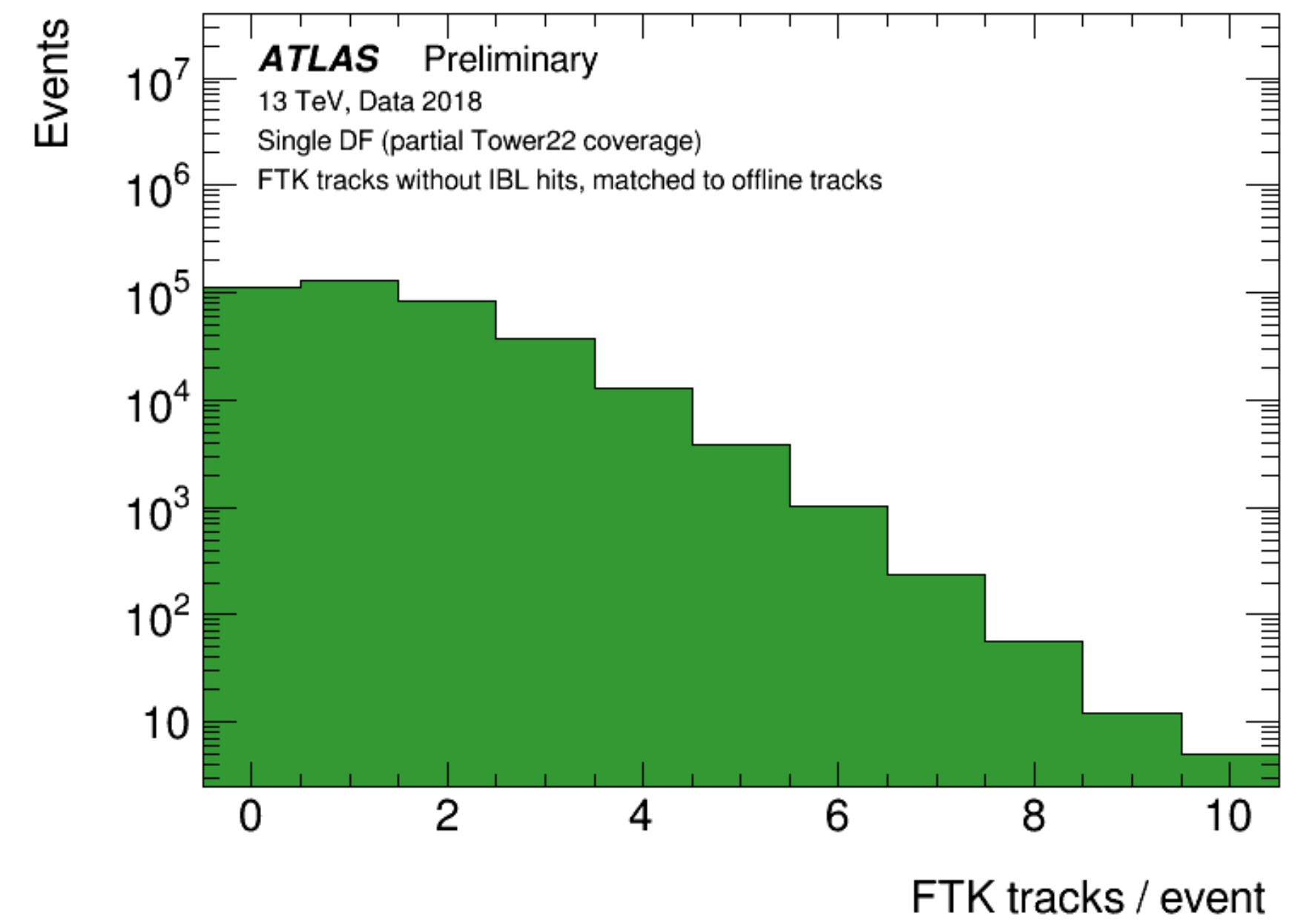
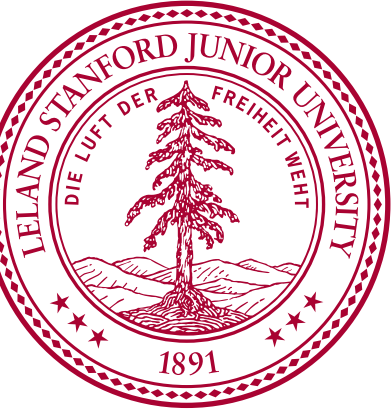


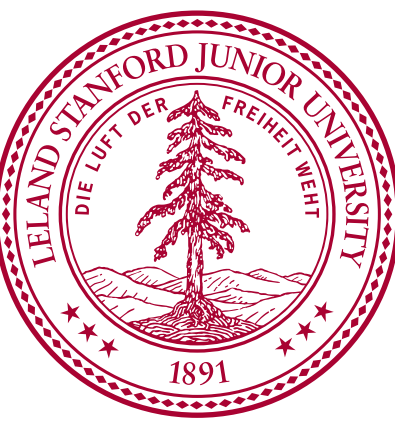
Track Fitter (TF):

Fits track with each combination of possible candidates, takes one with best χ^2 .
(Nominal and Pix/SCT Majority Fitters)



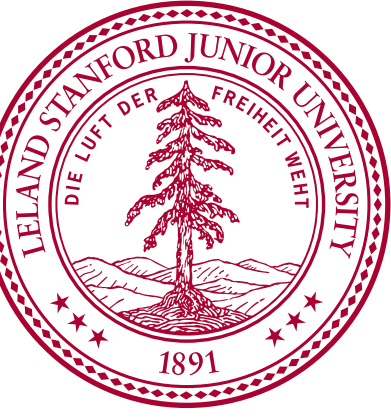
SLICE DATA IN 2018



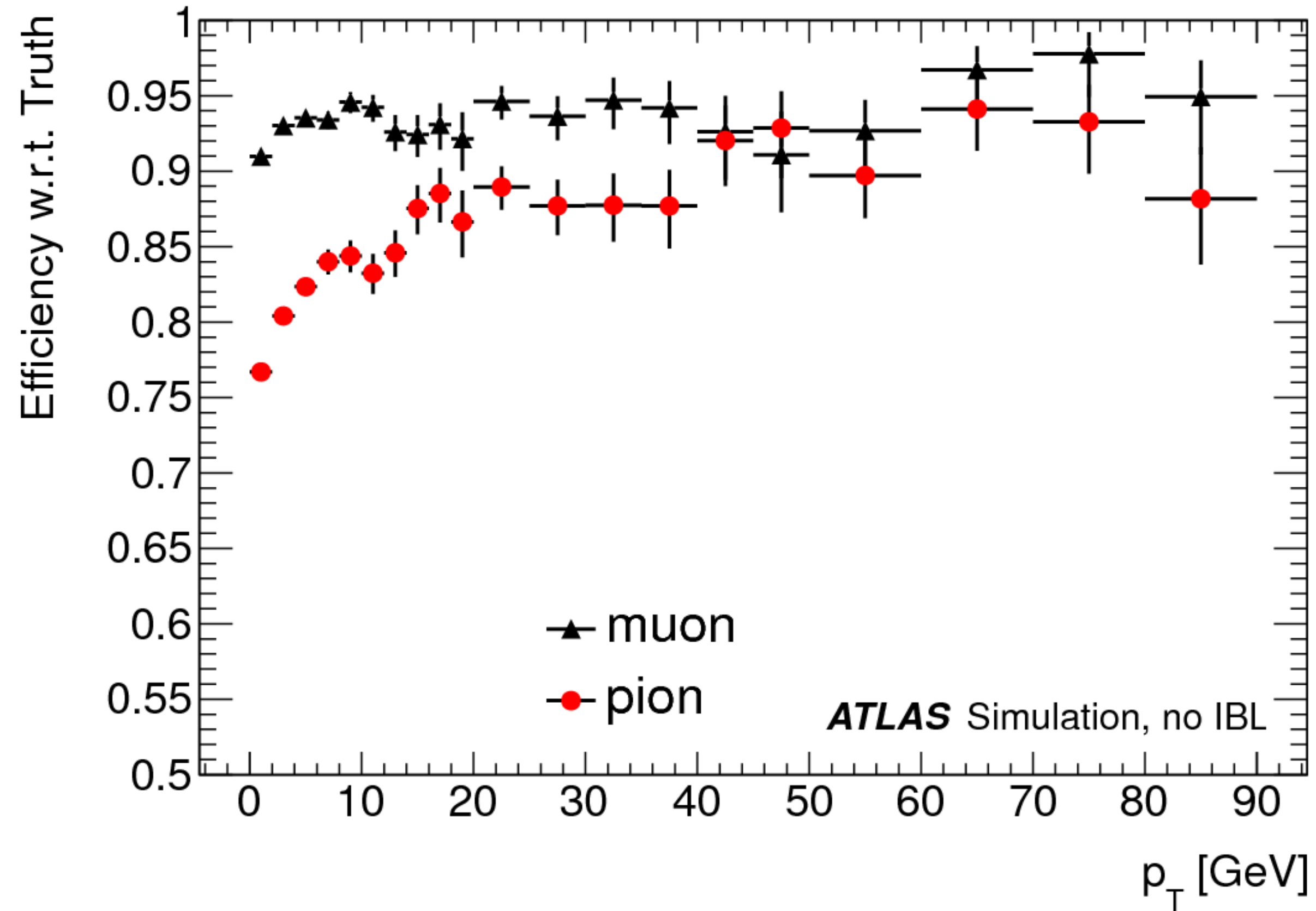


FTK AS A SYSTEM

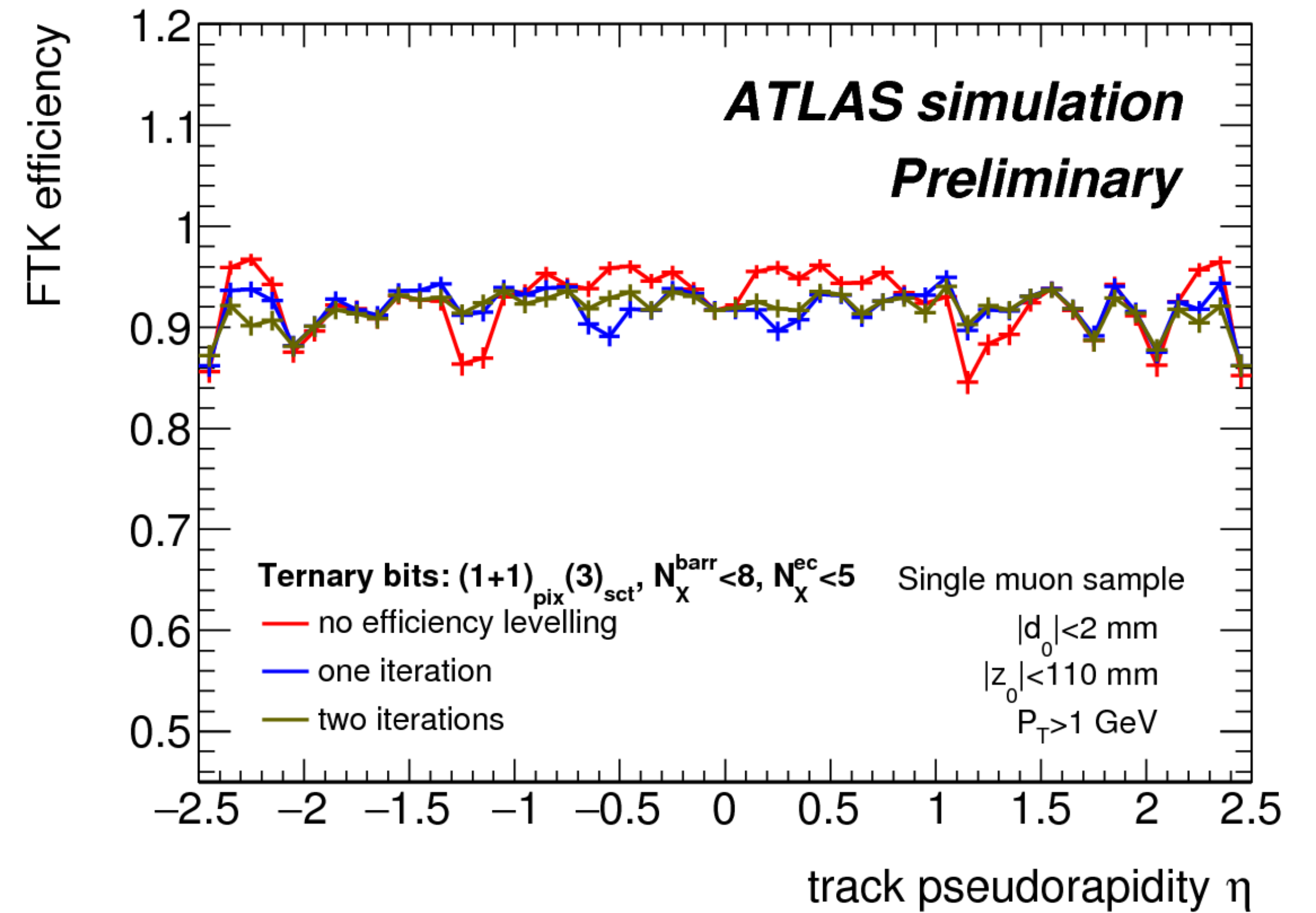
PERFORMANCE



EXPECTED PERFORMANCE



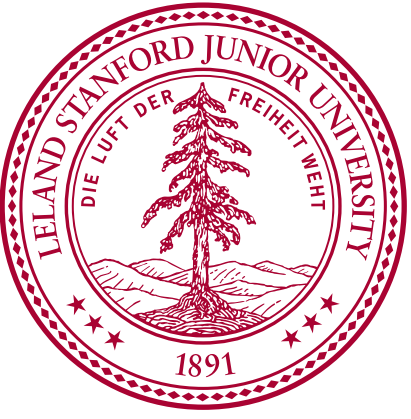
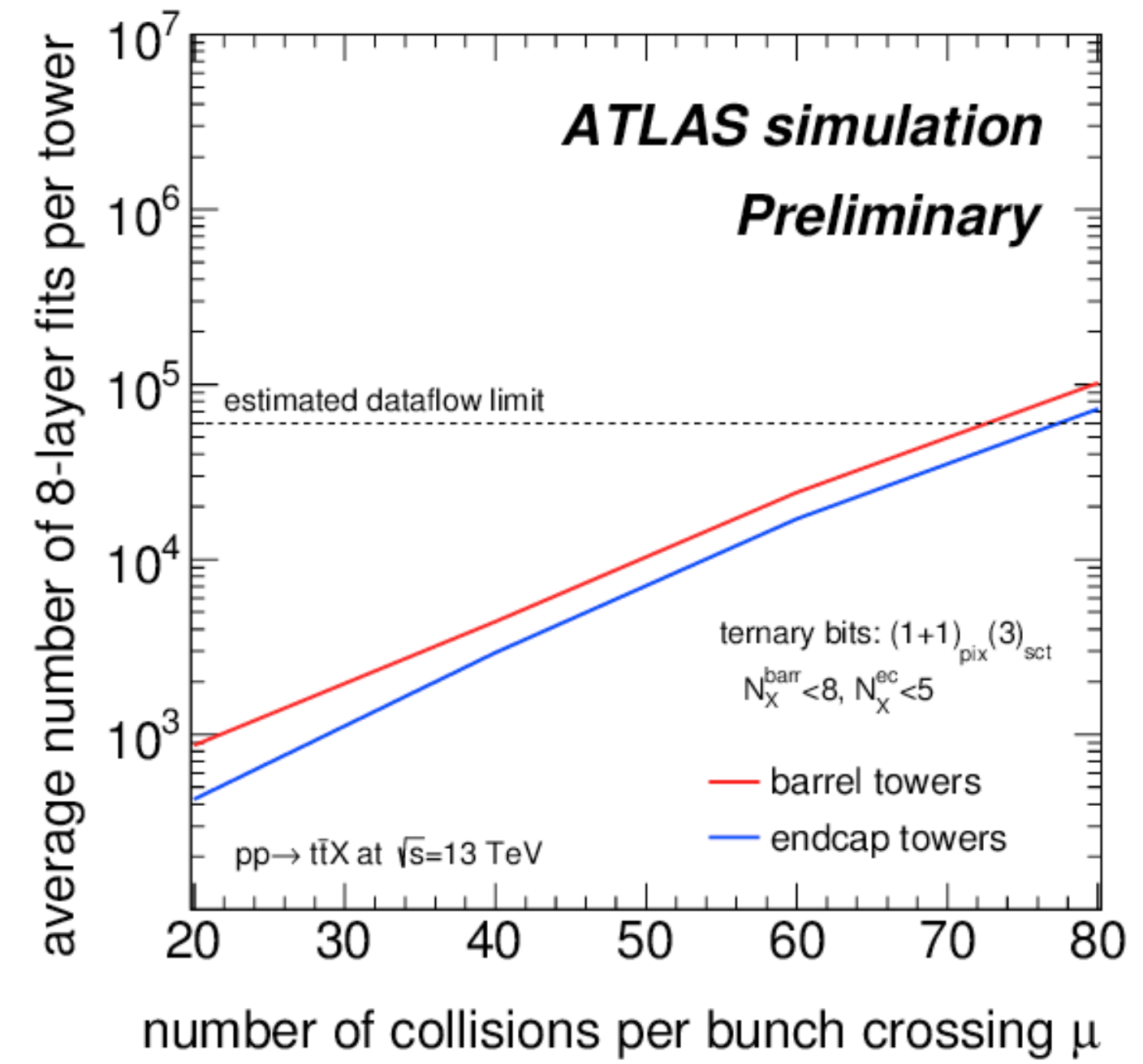
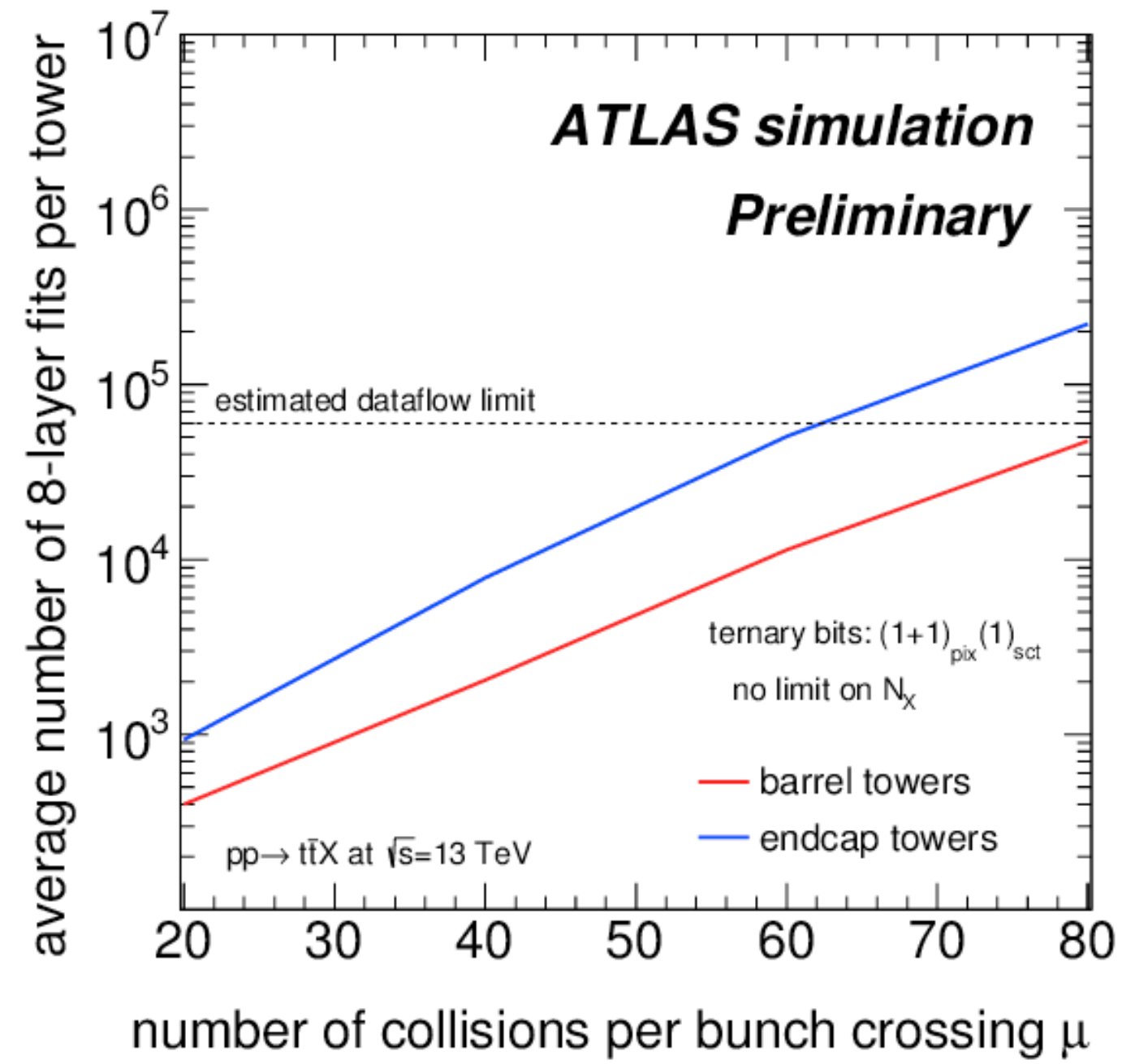
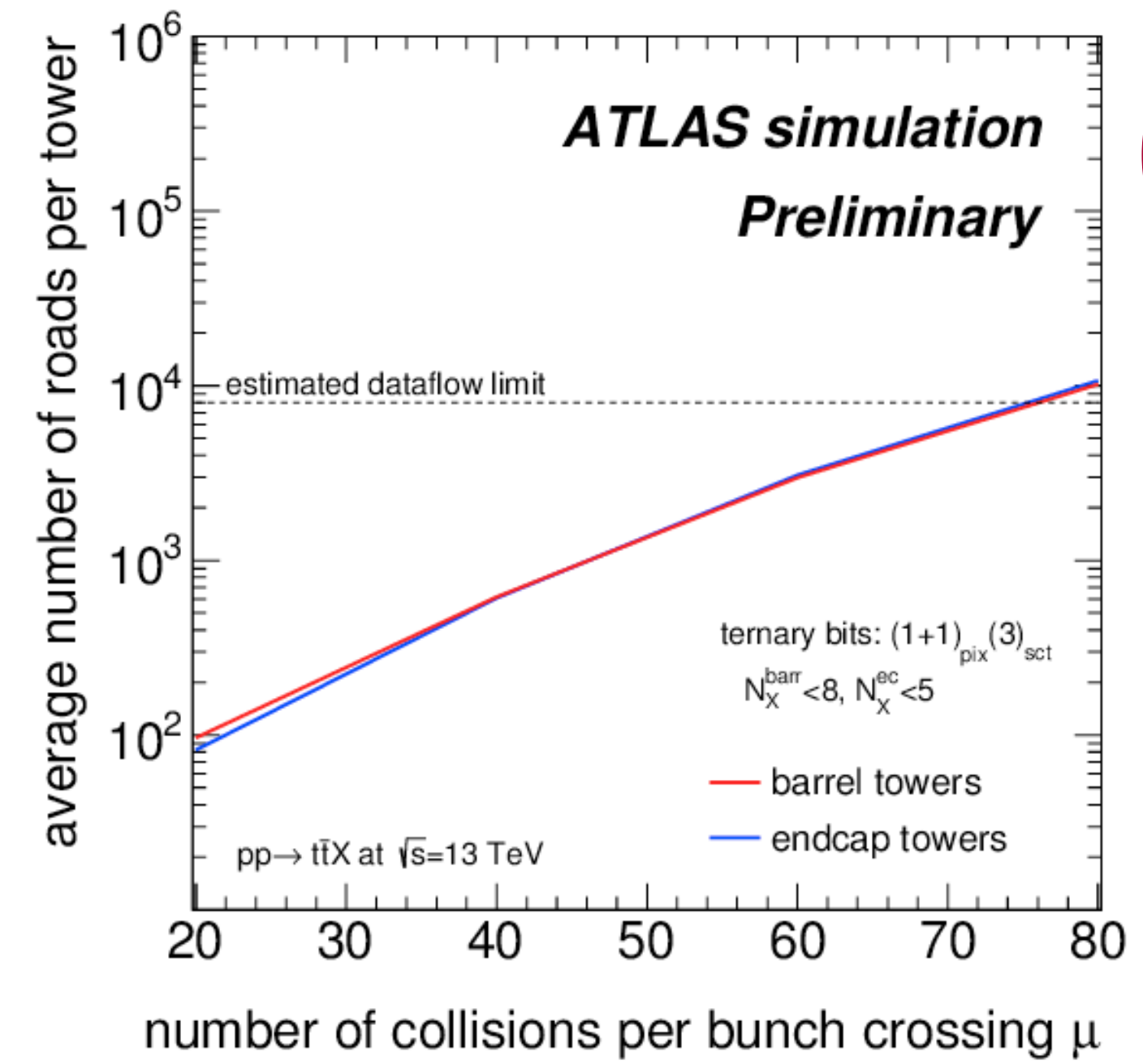
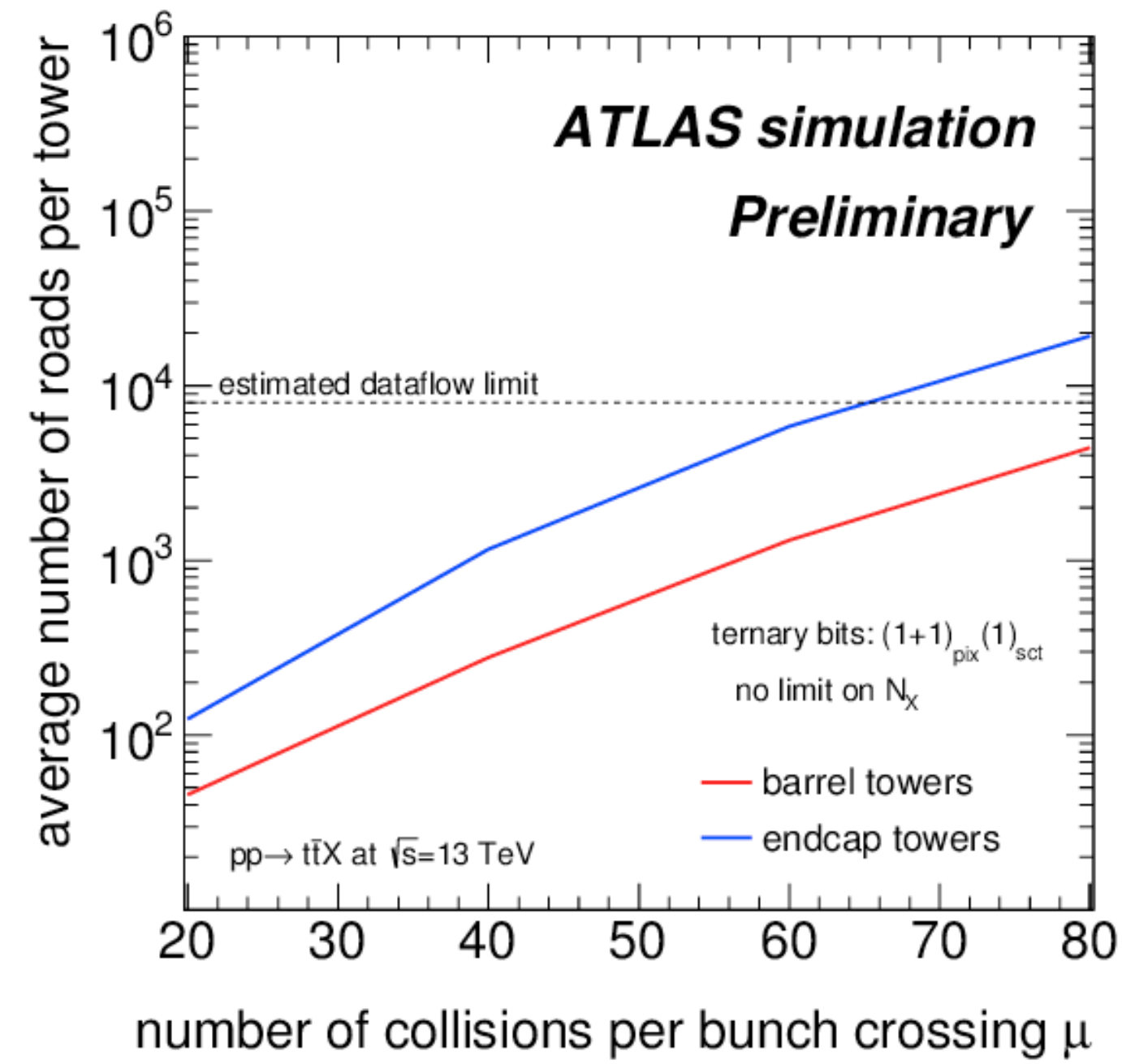
TDR, Optimistic



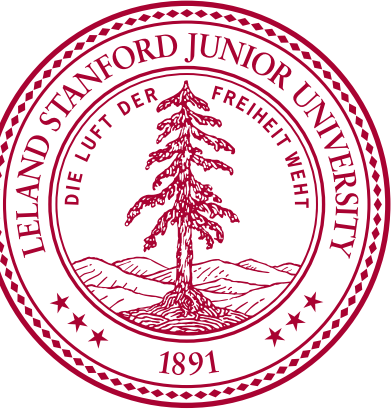
More realistic

DATAFLOW

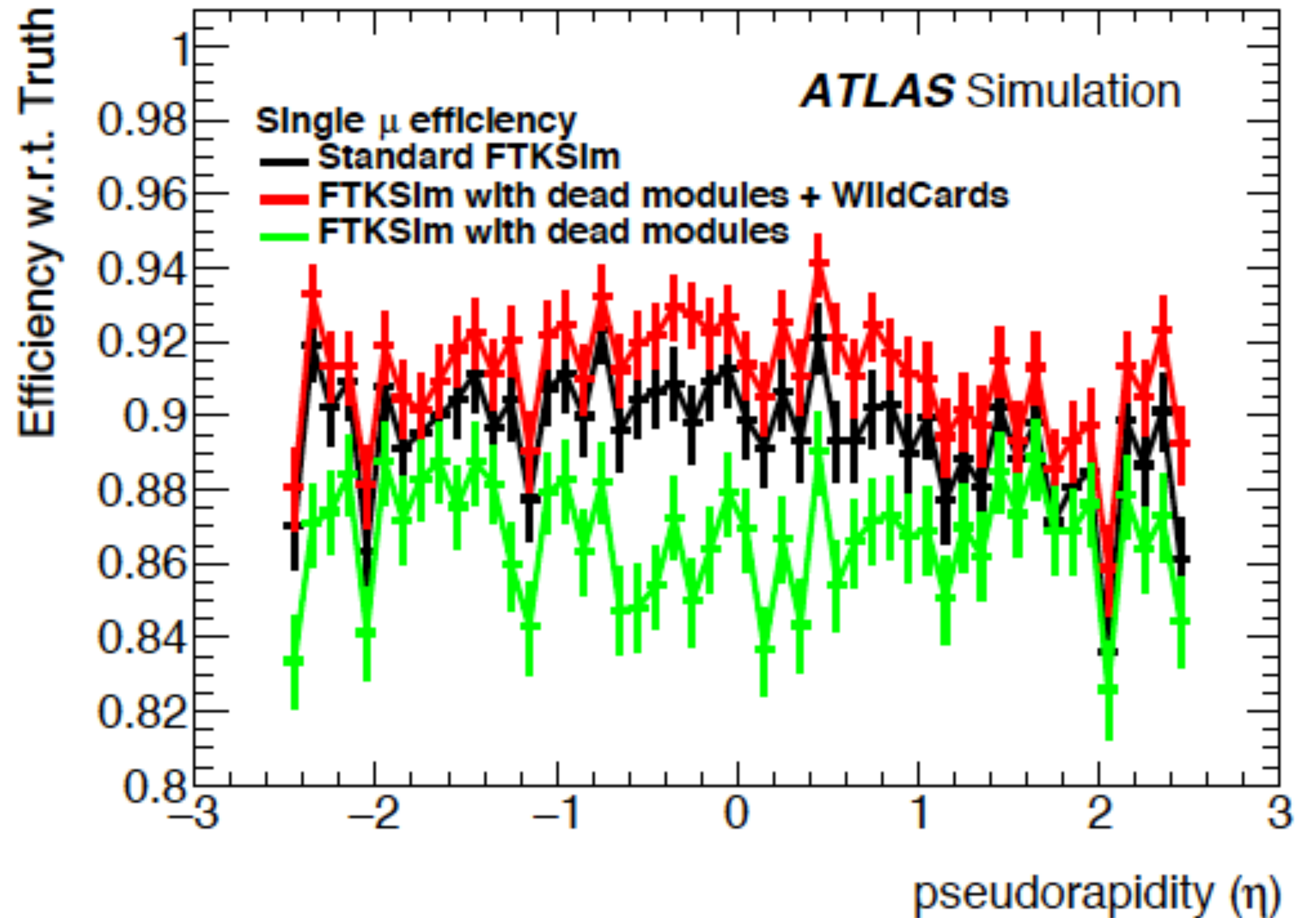
- Challenge was to have pattern banks efficient (~90%) but giving reasonable data flow
- Many configuration handles:
 - Pattern size
 - Pattern variability

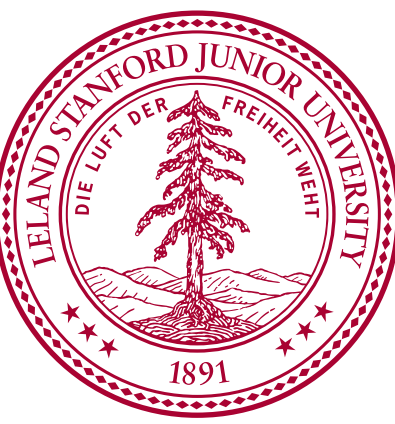


DETECTOR PERFORMANCE



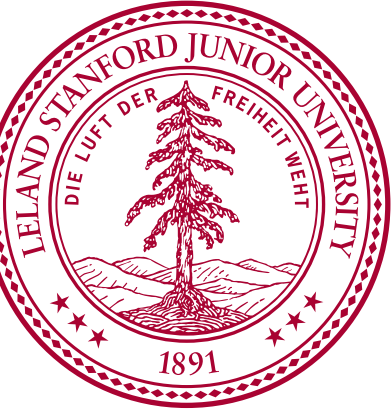
- Detector performance strongly effects efficiency
- Use wildcards to address this
 - Cost of higher dataflow





FTK AS A SYSTEM

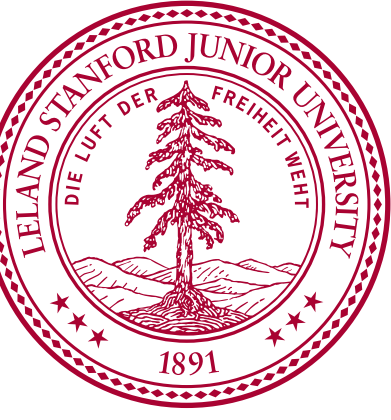
LESSONS LEARNED



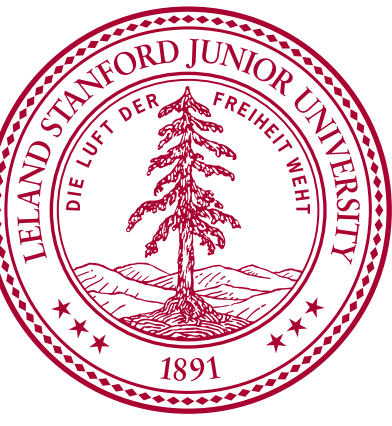
THE HIGHLIGHTS

- Heterogeneous systems are difficult to integrate and debug:
 - Mixed ATCA/VME ; mixed Xilinx/Altera — good reasons at the time but made life more challenging
- Resource usage estimates are hard without firmware in hand — nearly every FPGA was full
- Data push architecture with no external synchronization source is difficult in real (buggy) conditions
- Need significant engineering involvement of firmware writing
 - HLS was not mature when much of FTK development was happening (FW development started in ~2012)
- Early emphasis on interfaces/unit tests/CI&CD/simulation test benches would've streamlined integration and development
- Monitoring FW and online software is critical for debugging in situ
- Dedicated person-power is critical!

REFERENCES

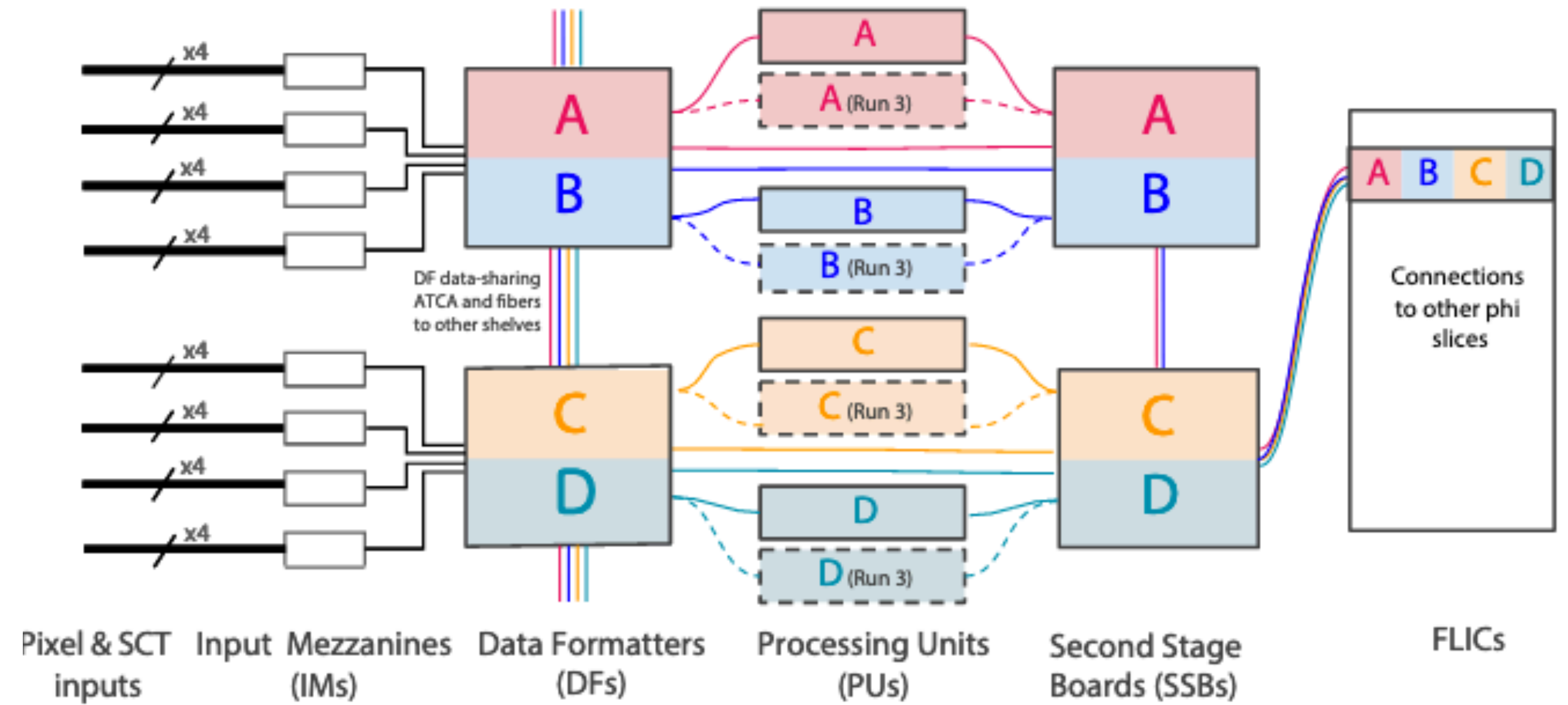
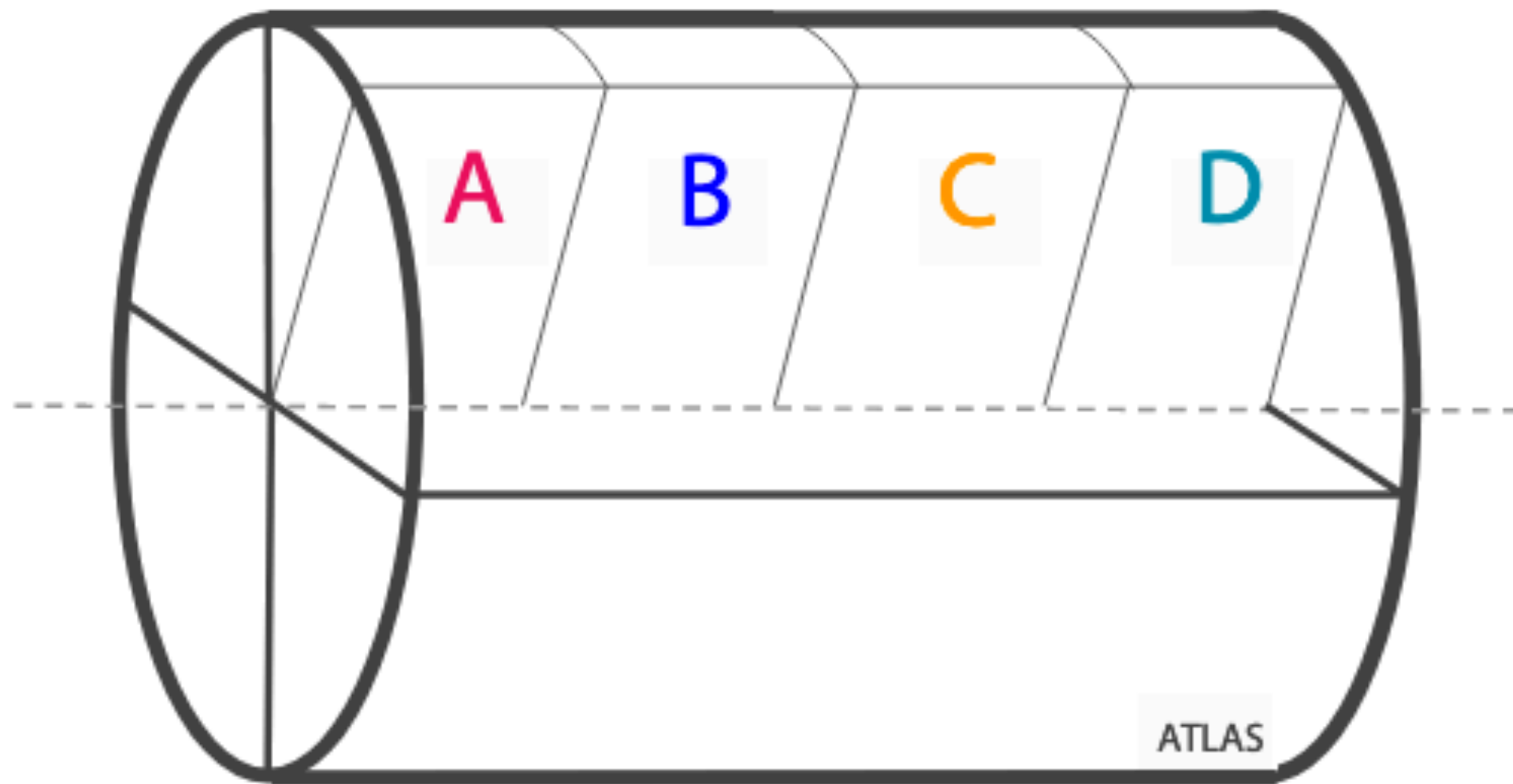
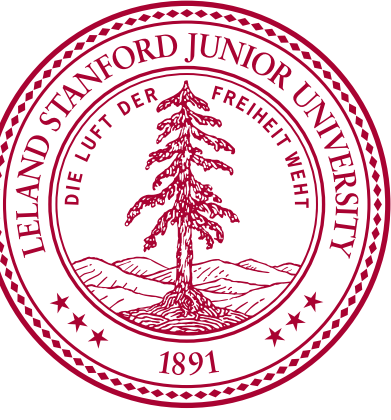


- FTK Technical Proposal and FTK Technical Design Report
- Original AMChip paper ; SVT Gigafitter reference
- FTK Sim proceedings
- FTK NIM paper on the arXiv soon! (next few weeks)

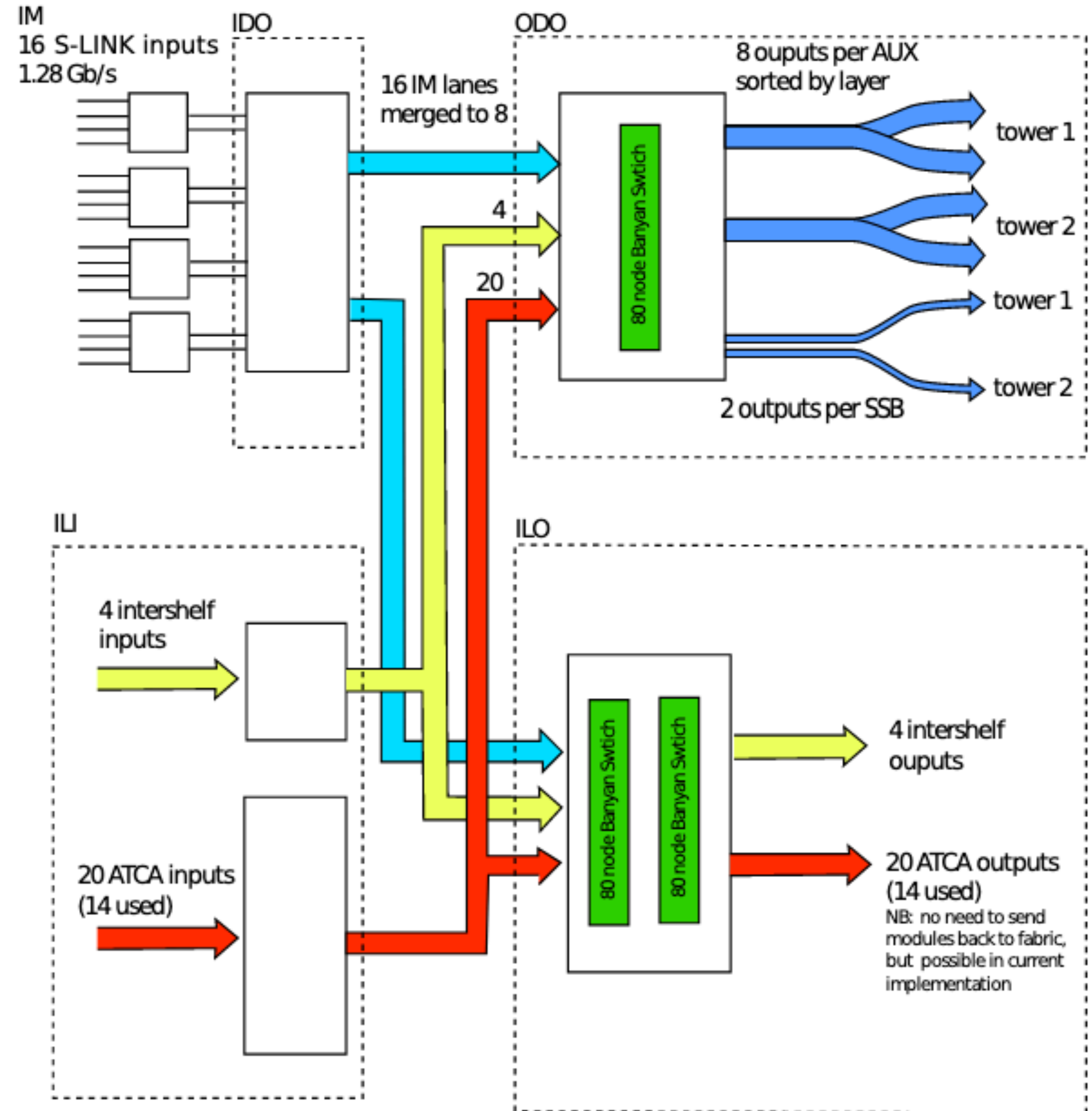


THE END

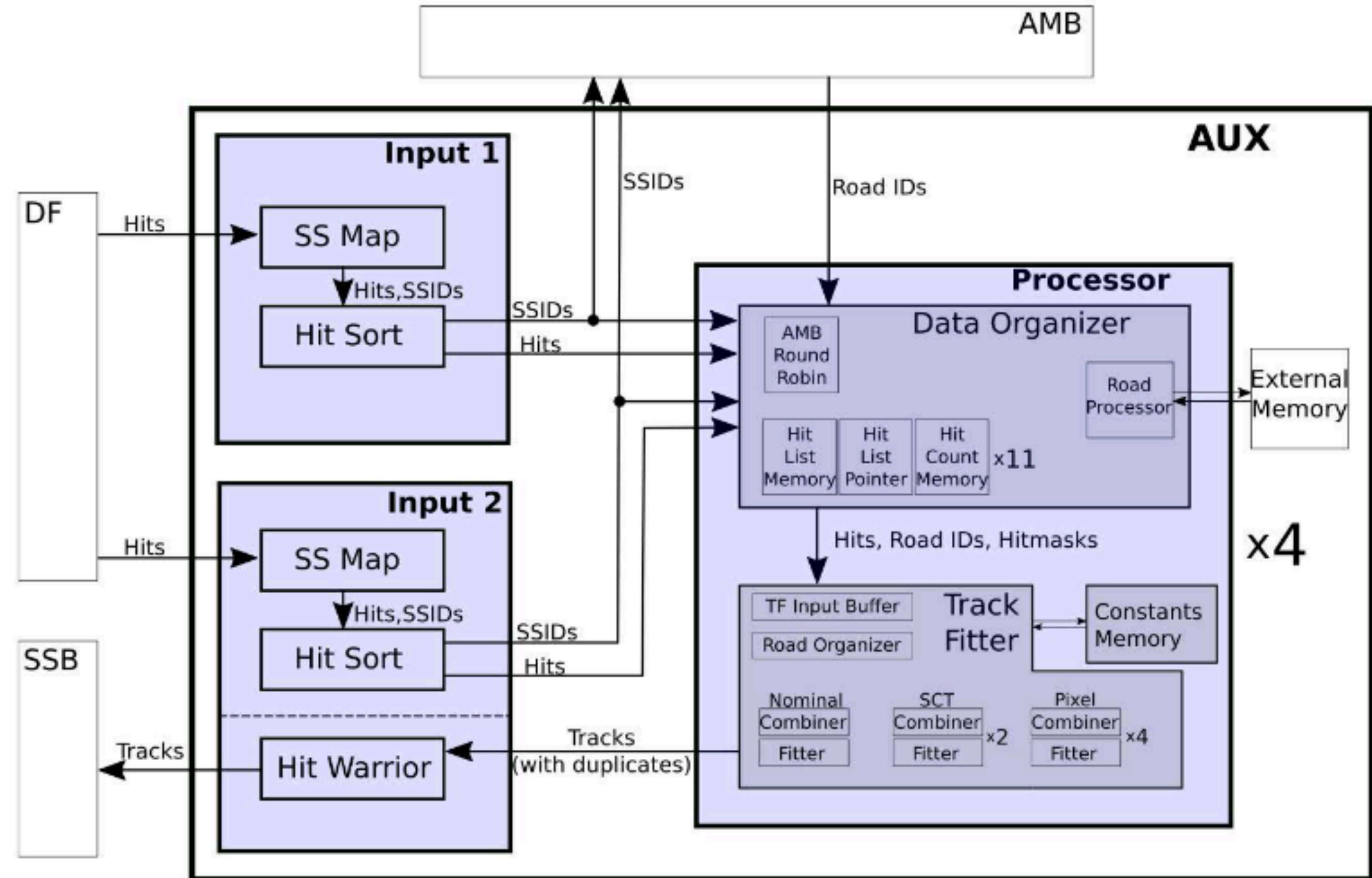
TOWER GEOMETRY



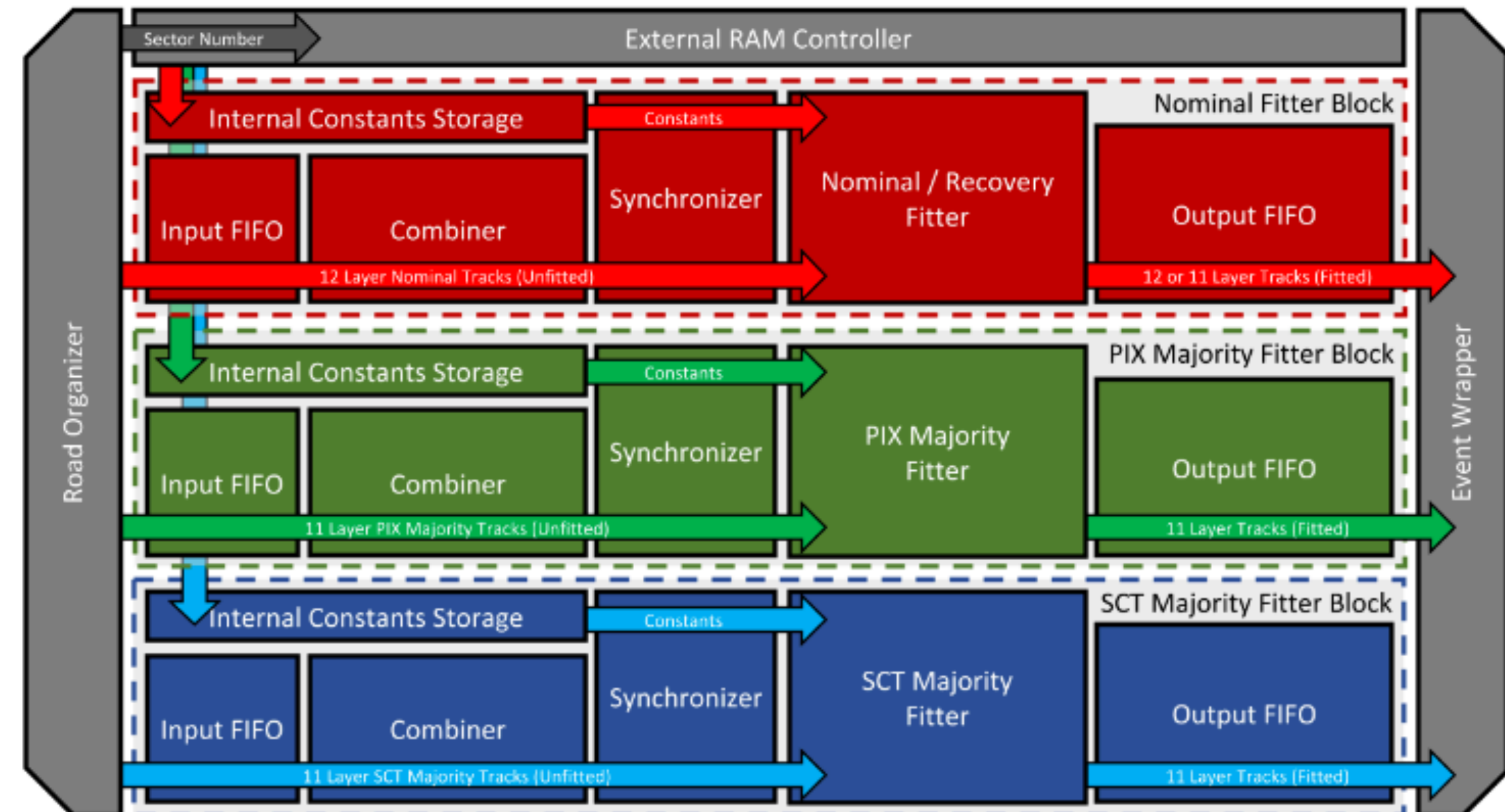
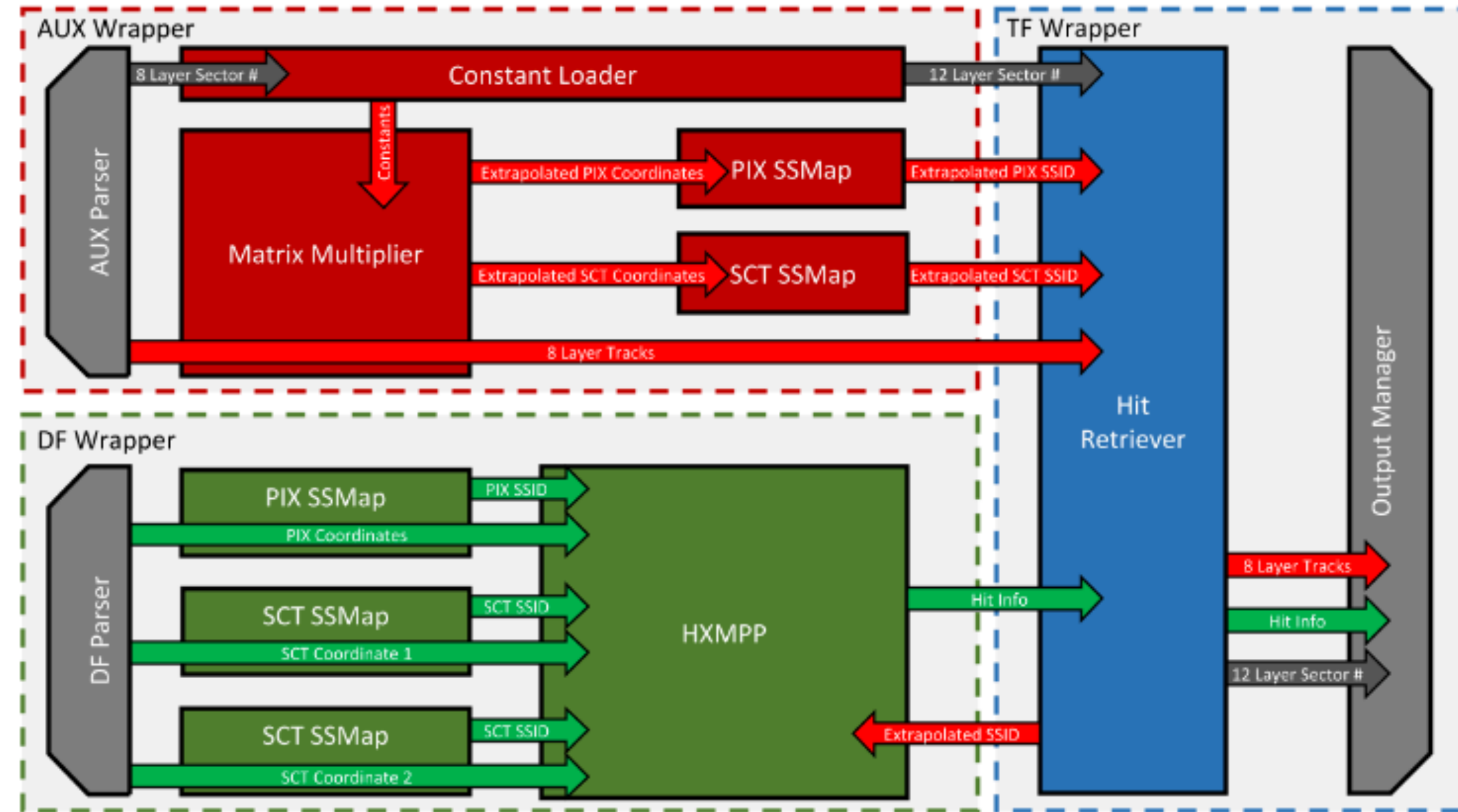
DATA FORMATTER LOGIC



AUX LOGIC

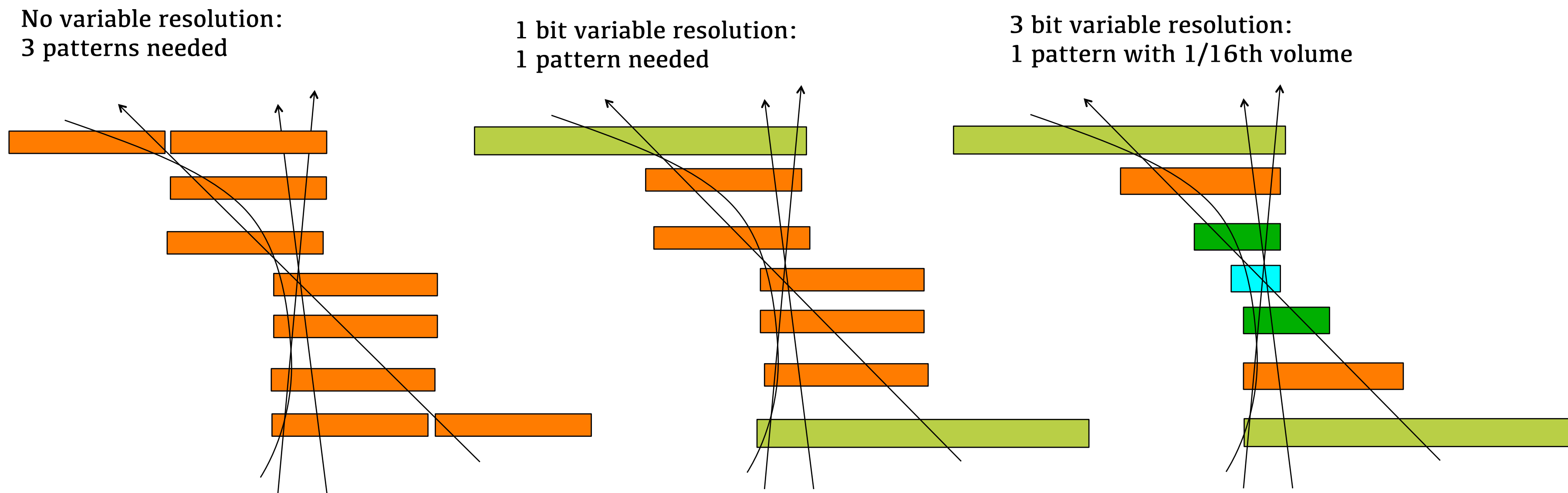


SSB LOGIC



REFINEMENTS

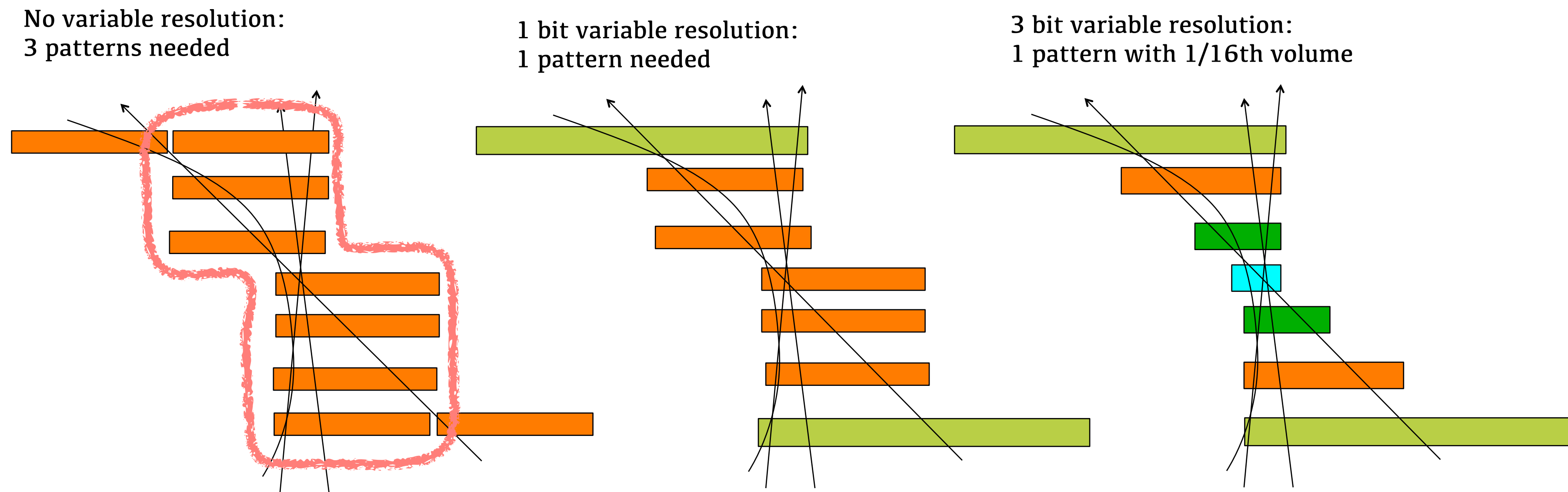
- Majority Logic: Only require N out of M layers have a match
 - Gains efficiency
- Variable Resolution Patterns (Don't Care Bits)
 - Reduces the number of patterns and fake matches



- Number of don't care bits set on a layer by layer, pattern by pattern basis

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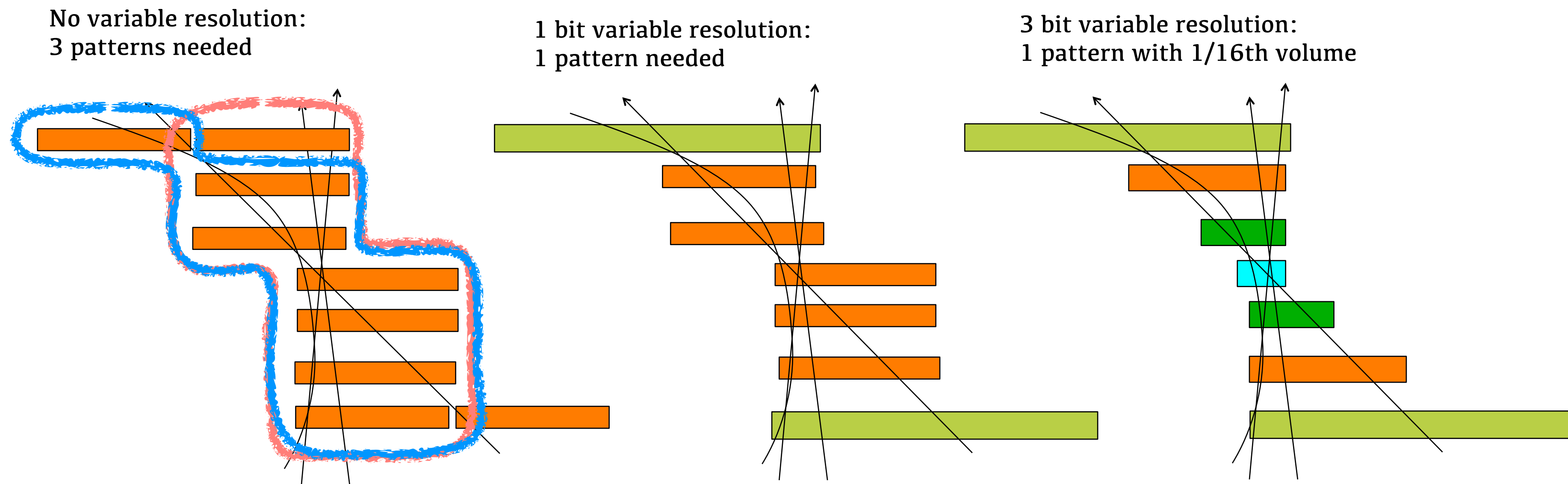
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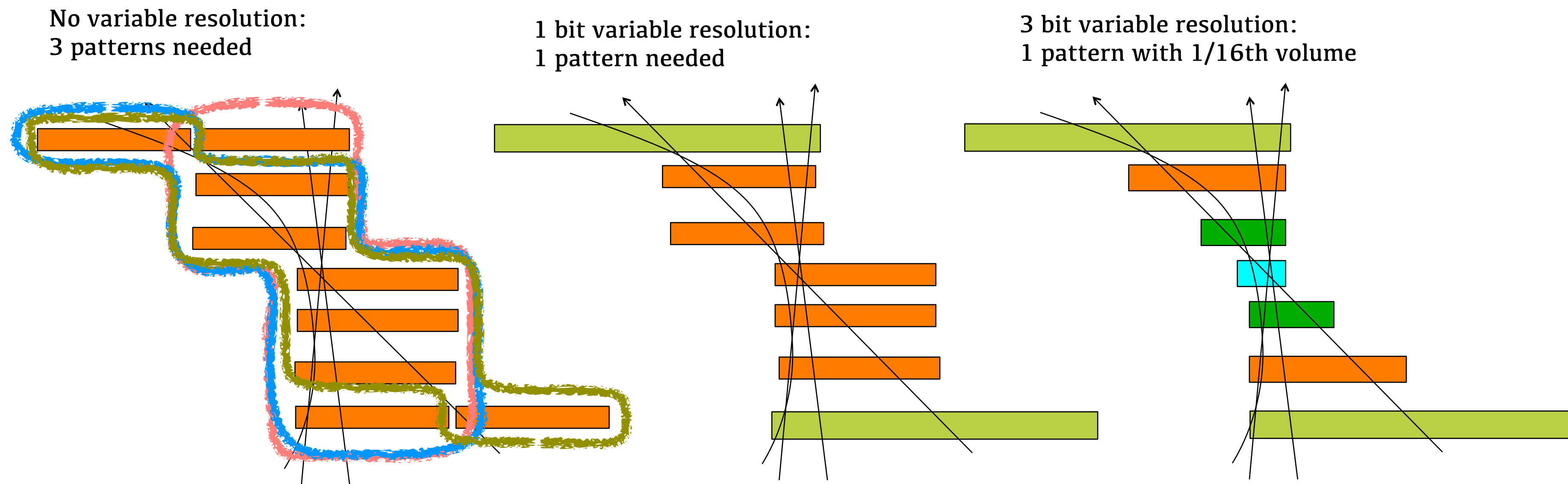
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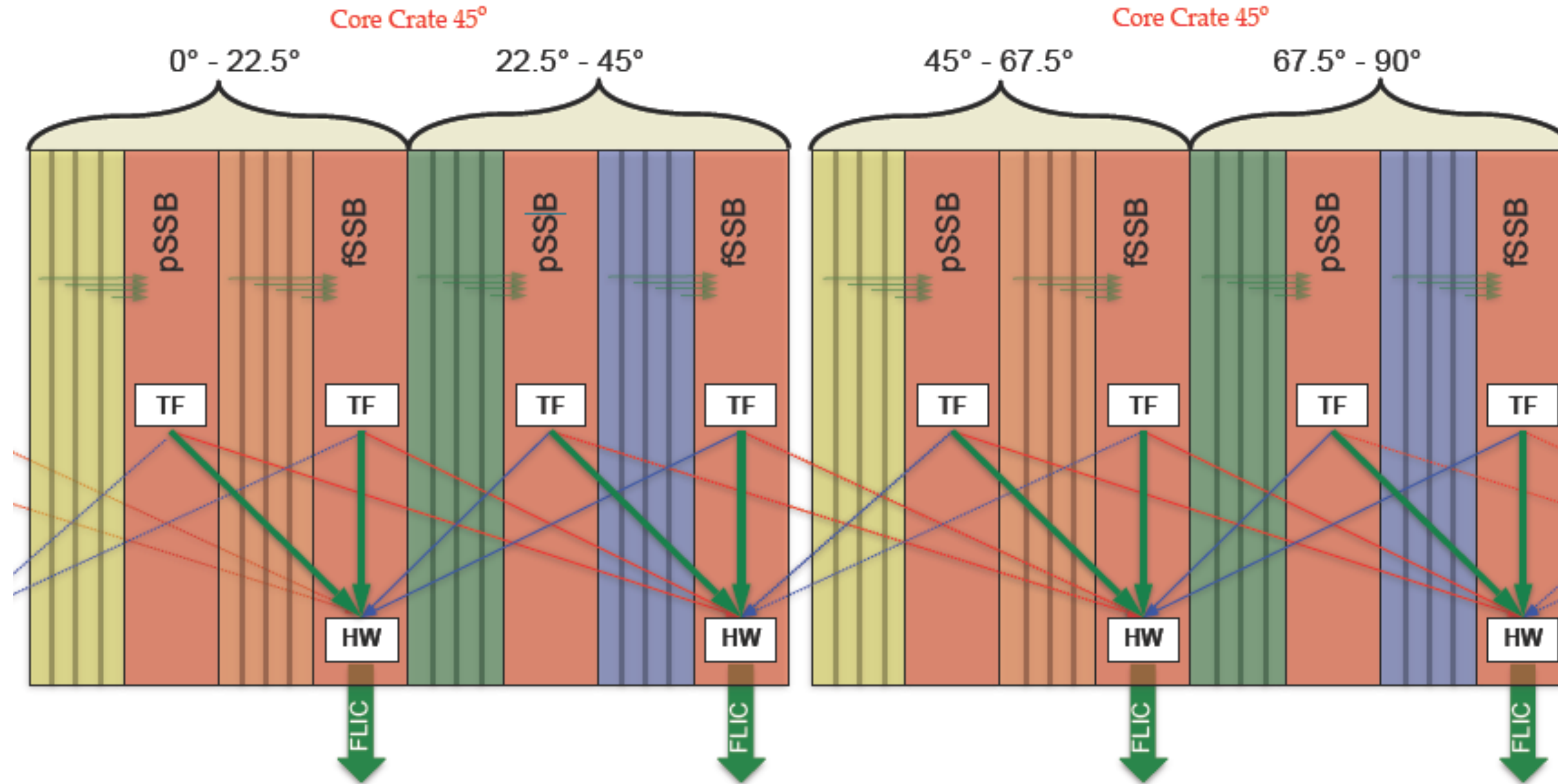
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HW: SSB track flow



Green arrows show the flow of tracks. Tracks flow out of the TF and are merged in the HW. **Red** and **Blue** arrows show tracks sent to neighboring ϕ regions for overlap removal

FLIC functionality

- Receive event records from upstream FTK system, 1/16th of the detector per channel
 - Full bandwidth output from the FLIC to HLT
 - Baseline: 300 tracks per event @ 100 kHz
- Convert FTK identifiers to ATLAS global identifiers using SRAM lookup
- Repackage event record into standard ATLAS format
- Communicate with HLT
 - Sends records
 - receives xoff signal and propagates it upstream to FTK
- Monitoring and Processing on ATCA Blades via backplane

